Versal ACAP Packaging and Pinouts

Architecture Manual

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Revision History

The following table shows the revision history for this document.

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Overview

Introduction to Versal ACAP

Versal[™] adaptive compute acceleration platforms (ACAPs) combine Scalar Engines, Adaptable Engines, and Intelligent Engines with leading-edge memory and interfacing technologies to deliver powerful heterogeneous acceleration for any application. Most importantly, Versal ACAP hardware and software are targeted for programming and optimization by data scientists and software and hardware developers. Versal ACAPs are enabled by a host of tools, software, libraries, IP, middleware, and frameworks to enable all industry-standard design flows.

Built on the TSMC 7 nm FinFET process technology, the Versal portfolio is the first platform to combine software programmability and domain-specific hardware acceleration with the adaptability necessary to meet today's rapid pace of innovation. The portfolio includes six series of devices uniquely architected to deliver scalability and Al inference capabilities for a host of applications across different markets—from cloud—to networking—to wireless communications—to edge computing and endpoints.

The Versal architecture combines different engine types with a wealth of connectivity and communication capability and a network on chip (NoC) to enable seamless memory-mapped access to the full height and width of the device. Intelligent Engines are SIMD VLIW AI Engines for adaptive inference and advanced signal processing compute, and DSP Engines for fixed point, floating point, and complex MAC operations. Adaptable Engines are a combination of programmable logic blocks and memory, architected for high-compute density. Scalar Engines, including Arm[®] Cortex™-A72 and Cortex-R5F processors, allow for intensive compute tasks.

The Versal AI Core series delivers breakthrough AI inference acceleration with AI Engines that deliver over 100x greater compute performance than current server-class of CPUs. This series is designed for a breadth of applications, including cloud for dynamic workloads and network for massive bandwidth, all while delivering advanced safety and security features. AI and data scientists, as well as software and hardware developers, can all take advantage of the high-compute density to accelerate the performance of any application.



The Versal Prime series is the foundation and the mid-range of the Versal platform, serving the broadest range of uses across multiple markets. These applications include 100G to 200G networking equipment, network and storage acceleration in the Data Center, communications test equipment, broadcast, and aerospace & defense. The series integrates mainstream 58G transceivers and optimized I/O and DDR connectivity, achieving low-latency acceleration and performance across diverse workloads.

The Versal Premium series provides breakthrough heterogeneous integration, very high-performance compute, connectivity, and security in an adaptable platform with a minimized power and area footprint. The series is designed to exceed the demands of high-bandwidth, compute-intensive applications in wired communications, data center, test & measurement, and other applications. Versal Premium series ACAPs include 112G PAM4 transceivers and integrated blocks for 600G Ethernet, 600G Interlaken, PCI Express® Gen5, and high-speed cryptography.

The Versal architecture documentation suite is available at: https://www.xilinx.com/versal.

Navigating Content by Design Process

Xilinx® documentation is organized around a set of standard design processes to help you find relevant content for your current development task. This document covers the following design processes:

- System and Solution Planning: Identifying the components, performance, I/O, and data transfer requirements at a system level. Includes application mapping for the solution to PS, PL, and Al Engine. Topics in this document that apply to this design process include:
 - Device/Package Combinations
 - Footprint Compatibility between Packages
 - Chapter 2: Die Level Bank Numbering and Device Diagrams
- **Board System Design:** Designing a PCB through schematics and board layout. Also involves power, thermal, and signal integrity considerations. Topics in this document that apply to this design process include:
 - Chapter 1: Overview describes the architecture, package resources, and footprint compatibility between packages.
 - Device Diagrams Overview, Chapter 3: Package Files, and Chapter 4: Device Diagrams describes the package pinouts in textual and graphical format.
 - Chapter 5: Mechanical Drawings includes the physical dimensions for each package.
 - Chapter 6: Package Marking and Chapter 7: Packing and Shipping.
 - Chapter 8: Soldering Guidelines, Chapter 9: Recommended PCB Design Rules for BGA, and Chapter 10: Edge Bonding Guidelines provide PCB implementation information.



 Chapter 11: Thermal Specifications, Chapter 12: Thermal Management Strategy, Chapter 13: Heat Sink Guidelines for Bare-die VB Packages, and Chapter 14: Mechanical and Thermal Design Guidelines for Lidless Flip-chip Packages include guidelines for overall thermal management.

Package and Pinout Overview

This section describes the packages and pinouts for various organic flip-chip 0.80 mm, 0.92 mm, and 1.00 mm pitch BGA packages.



IMPORTANT! All standard packages are lead-free (signified by an additional V in the package name). All devices supported in a particular package are footprint compatible. Each device is split into I/O banks to allow for flexibility in the choice of I/O standards. See the Versal ACAP SelectIO Resources Architecture Manual (AM010).

The flip-chip assembly materials for the Versal devices are manufactured using ultra-low alpha (ULA) materials defined as <0.002 cph/cm² or materials that emit less than 0.002 alpha-particles per square centimeter per hour.



IMPORTANT! All packages are available with eutectic BGA balls. To order these packages, the device type starts with an XQ vs. XC or XA, and the Pb-free signifier in the package name is Q.

Device/Package Combinations

The following table shows the size and BGA pitch of the Versal device packages. All packages are available with eutectic BGA balls. For these packages, the Pb-free signifier in the package name is a Q.



Table 1: Package Specifications

			Package Specifications			
Packages	Description	Package Type	Pitch (mm)	Size (mm)	LSC Ball Grid Size (balls)	
SFVB625	Super-fine pitch with forged lid	BGA	0.8	21 × 21	-	
VBVA1024	Fine pitch bare-die		0.92	31 × 31	4 × 4	
VFVB1024	Fine pitch with forged lid			31 × 31	4 × 4	
VFVB1369	Fine pitch with forged lid			35 × 35	5 × 5	
VSVE1369	Fine pitch lidless with stiffener ring			35 × 35	5 × 5	
VSVA1596	Fine pitch lidless with stiffener ring			37.5 × 37.5	5 × 5	
VIVA1596	Overhang fine pitch lidless with stiffener ring			40 × 40	6 × 6	
VFVA1760	Fine pitch with forged lid			40 × 40	6 × 6	
VFVC1760	Fine pitch with forged lid			40 × 40	6 × 6	
VSVD1760	Fine pitch lidless with stiffener ring			40 × 40	6 × 6	
VSVA2197	Fine pitch lidless with stiffener ring			45 × 45	7 × 7	
VSVA2785	Fine pitch lidless with stiffener ring			50 × 50	9 × 9	



IMPORTANT! Packages with land-side capacitors (LSC) include a region of the BGA matrix where the BGA balls are replaced with capacitors. The LSC Ball Grid Size column in Table 1 describes the size of the LSC region in terms of the number of BGA balls replaced by capacitors. Therefore, packages with LSCs have fewer balls than the package name implies (for example, the VSVA2197 has $7 \times 7 = 49$ fewer balls than the implied 2197 balls).

Gigabit Transceiver Channels by Device/ Package

The following table lists the quantity of gigabit transceiver channels for the Versal devices. There is one set of MGTRXP, MGTRXN, MGTTXP, and MGTTXN pins for the GTY or GTM channels in all devices. All packages are available with eutectic BGA balls where the device type is XQ and the Pb-free signifier in the package name is a Q.

Table 2: Serial Transceiver Channels (GTY and GTM) by Device/Package

Device	Package	GTY Channels	GTM Channels
VM1102	SFVB625	4	0
VC1352	VBVA1024	8	0
VC1502		8	0



Table 2: Serial Transceiver Channels (GTY and GTM) by Device/Package (cont'd)

Device	Package	GTY Channels	GTM Channels
VM1102	VFVB1024	12	0
VM1302		16	0
VM1402		16	0
VM1302	VFVB1369	24	0
VM1402		24	0
VM1502		16	0
VM1302	VFVF1369	8	0
VM1402		8	0
VC1352	VSVE1369	8	0
VC1702		24	0
VC1502	VSVG1369	24	0
VC1502	VSVA1596	32	0
VC1702		16	0
VC1802	VIVA1596	32	0
VC1902		32	0
VM1302	VFVA1760	24	0
VM1402		24	0
VM2602		8	24
VM1502	VFVC1760	44	0
VM1802		44	0
VM2602		8	40
VM2902		8	40
VM1802	VSVD1760	24	0
VC1802	VSVD1760	24	0
VC1902		24	0
VM1802	VSVA2197	44	0
VM2502		16	16
VC1502	VSVA2197	44	0
VC1802		44	0
VC1902		44	0



Differences from Previous Generations

This section lists the differences from previous generations of the packaging and pinout specifications.

- In addition to 0.8 mm and 1.0 mm BGA ball pitch, Versal ACAP packages have 0.92 mm BGA ball pitch, signified by a package code beginning with a V.
- Some packages include land-side capacitor (LSC) technology (decoupling capacitors on the bottom side of the package, adjacent to the BGA balls). LSC array dimensions for each package are found in Chapter 5: Mechanical Drawings.
- Hardware blocks bonded to package pins have been added with Versal™ ACAPs, including XPIO, PMCMIO, and LPDMIO banks.
- I/Os in some banks on the left and right edges of the XPIO rows do not have direct access to all I/O logic resources and can only be used for DDR memory controller (DDRMC) applications.
- VRP pins, previously found in each HPIO bank, are replaced with a single IO_VR pin for each row of XPIO banks.
- V_{CCO} voltage range for XPIO banks is 1.0V to 1.5V instead of the 1.0V to 1.8V range for HPIO banks in previous generations.
- Device diagrams showing package pinout (previously separated into I/O diagrams and power/ dedicated/multifunction diagrams, are combined into a single diagram for Versal ACAP packages.
- Package marking found on previous device generations is replaced with a 2D bar code.

User I/O Pins by Device Package

The following table lists the number of available PMC and LPD multiplexed I/Os (MIO), 3.3V-capable high-density (HD), and 1.5V-capable high-performance (XP) I/Os and the number of HD or XP differential I/O for each device/package combination. All packages are available with eutectic BGA balls where the device type is XQ and the Pb-free signifier in the package name is a Q.

Table 3: Available I/O Pins by Device/Package

Device Package	ackage MIO -		Total User I/O		Differential I/O	
	IVITO	XPIO	HDIO	XPIO	HDIO	
VC1352	VBVA1024	78	378	22	189	11
	VSVE1369	78	378	44	189	22



Table 3: Available I/O Pins by Device/Package (cont'd)

Device	Package	MIO	Total User I/O		Differential I/O	
		MIO	XPIO	HDIO	XPIO	HDIO
VC1502	VBVA1024	78	378	22	189	11
	VSVG1369	78	378	44	189	22
	VSVA1596	78	378	44	189	22
	VSVA2197	78	378	44	189	22
VC1702	VSVE1369	78	378	44	189	22
	VSVA1596	78	378	44	189	22
VC1802	VIVA1596	78	378	44	189	22
	VSVD1760	78	648	0	324	0
	VSVA2197	78	648	44	324	22
VC1902	VIVA1596	78	378	44	189	22
	VSVD1760	78	648	0	324	0
	VSVA2197	78	648	44	324	22
VM1102	SFVB625	78	216	22	108	11
	VFVB1024	78	216	22	108	11
VM1302	VFVB1024	78	216	22	108	11
	VFVB1369	78	216	22	108	11
	VFVF1369	78	324	22	162	11
	VFVA1760	78	432	22	216	11
VM1402	VFVB1024	78	324	22	162	11
	VFVB1369	78	324	22	162	11
	VFVF1369	78	648	22	324	11
	VFVA1760	78	648	22	324	11
VM1502	VFVB1369	78	378	44	189	44
	VFVC1760	78	378	44	189	44
VM1802	VFVC1760	78	378	44	189	44
	VSVD1760	78	648	0	324	0
	VSVA2197	78	648	44	324	22
VM2502	VSVA2197	78	648	22	324	11
VM2602	VFVA1760	78	756	0	378	0
	VFVC1760	78	378	0	189	0
VM2902	VFVC1760	78	378	22	189	11

Notes:

^{1.} The maximum user I/O numbers do not include the GT serial transceiver pins.



Pin Definitions

The following tables list the pin definitions.

SelectIO Pin Definitions

Table 4: SelectIO Pin Definitions

Pin Name	Direction	Description
IO	Bidirectional	Pin name consists of: L[1 to 24][P or N]: Differential pair number with P (positive) and N (negative) N[0 to 8]P[0 to 5]: XPHY nibble number and pin number within the nibble (NIBBLESLICE number) M[0 to number of triplets]P[0 to 161]: Triplet number and pin within the triplet [bank number]: Bank number The XP IOB block provides resources to enable high-speed interfaces between the programmable logic (PL) and the system outside the device. The XP IOB resources are designed to accommodate the signaling needs for high-speed memory and chip-to- chip interfaces that are powered between 1.0V and 1.5V. The XP IOB provides internal termination, internal reference generation, support for a diverse set of I/O standards, driver emphasis, and receiver equalization. These features allow the XP IOB to integrate with a diverse range of systems.
		High-density (HD) I/O banks are resources designed to support I/O standards with voltages ranging from 1.8V to 3.3V. HD I/Os support single ended and pseudo-differential I/O bidirectional signaling operating at data rates of up to 400 Mb/s. Limited support for true differential inputs (with external termination) is also available to support LVDS and LVPECL clock inputs. HD I/O banks contain interface logic (HD IOL) that includes registers, a DPLL, and static delay lines to support asynchronous, system synchronous, and clock-based source synchronous interfaces.
GC/HDGC	Bidirectional	Global clock (GC) inputs provide dedicated, high-speed access to the internal global and regional clock resources. GC inputs use dedicated routing and must be used for clock inputs where the timing of various clocking features is imperative. General-purpose I/O with local interconnects must not be used for clock signals.
IO_VR	N/A	This pin is for the DCI voltage reference resistor, one per bank row: IO_VR_700 and IO_VR_800. Tie to VCCO_700 and VCCO_800, respectively, with a reference resistor.

Power Pin Definitions

Table 5: Power Pin Definitions

Pin Name	Direction	Description
VCCINT	N/A	Power-supply pins for the programmable logic, AI Engines, and CPM
VCCAUX	N/A	Power-supply pins for the auxiliary circuits
VCC_IO	N/A	Power-supply pins for the HDIO and XPIO banks
VCCO (XPIO or HDIO)	N/A	Power-supply pins for the output drivers (per bank)



Table 5: Power Pin Definitions (cont'd)

Pin Name	Direction	Description
VCCO_500	N/A	PMC MIO bank 0 power supply
VCCO_501	N/A	PMC MIO bank 1 power supply
VCCO_502	N/A	LPD MIO bank power supply
VCCO_503	N/A	PMC dedicated I/O bank power supply
VCCAUX_PMC	N/A	Auxiliary power-supply pin for the PMC
VCC_PSFP	N/A	Power-supply for the PS full-power domain
VCC_PSLP	N/A	Power-supply for the PS low-power domain
VCC_PMC	N/A	Auxiliary power-supply pins for the PMC
VCC_SOC	N/A	Power supply pins for NoC, NPI, and the DDR
VCC_RAM	N/A	Power-supply pins for the RAM, UltraRAM, and clocking network
VCC_BATT	N/A	Battery supply voltage
VCC_FUSE	N/A	Power-supply pins for eFUSE programming
VCCAUX_SMON	N/A	Analog supply pin for the ADC and other analog circuits in the SYSMON
GND_SMON	N/A	Ground reference pin for the ADC and other analog circuits in the SYSMON
GND	N/A	Ground
RSVDGND	N/A	Reserved pin. Tie to GND.
NC	N/A	Reserved pin. Leave floating

PMCMIO, LPDMIO, PMCDIO Pin Definitions

Table 6: PMCMIO, LPDMIO, PMCDIO Pin Definitions

Pin Name	Direction	Description
PMC_MIO[0 to 51]	Bidirectional	Platform management controller (PMC) multiplexed I/O (MIO)
LPD_MIO[0 to 25]	Bidirectional	Low-power domain (LPD) MIO
MODE[0 to 3]	Input	The MIO MODE selection pins are used to select the boot mode of the device. The value of these pins is captured on the rising edge of POR_B.
ERROR_OUT	Output	The ERROR_OUT pin is open drain with a weak internal pull-up. An external pull-up is recommended. ERROR_OUT is 3-stated and pulled High when an error occurs in the device.
RTC_PADO	Output	Real-time clock (RTC) crystal output
RTC_PADI	Input	RTC crystal input
PUDC_B	Input	The pull-up during configuration (PUDC_B) pin is used to select the behavior of the XPIO or HDIO during configuration. If the PUDC_B pin is High, then the XPIO and HDIO are put into tristate mode. If the PUDC_B is Low, then internal pull-ups at each XPIO and HDIO are enabled. The PUDC_B pin does not affect the PS or PMC I/O during boot and configuration.
DONE	Bidirectional	The DONE pin is open drain with a weak internal pull-up resistor. An external pull-up is recommended. DONE is tristated and pulled High when the boot sequence is complete.
REF_CLK	Input/Output	The reference clock is required for all boot modes. The REF_CLK is also the input clock to the PMC PLL and is required for the slave boot interface software register access.



Table 6: PMCMIO, LPDMIO, PMCDIO Pin Definitions (cont'd)

Pin Name	Direction	Description
POR_B	Input	Active-Low POR_B pin is the global power-on reset for the Versal device. It must remain asserted Low until power is fully applied to at least the VCC_PMC, VCCAUX_PMC, and VCCO_503. When the reset is released, the PMC begins the initialization and boot process.
тск	Input	JTAG test clock
TDI	Input	JTAG test data input
TDO	Output	JTAG test data output
TMS	Input	JTAG test mode select

GTY Transceiver Quad Pin Definitions

Table 7: GTY Transceiver Quad Pin Definitions

Pin Name	Direction	Description
GTY_RXP, GTY_RXN	Input	GTY_RXP and GTY_RXN are the differential input pairs for each of the receivers in the GTY transceiver Quad
GTY_TXP, GTY_TXN	Output	GTY_TXP and GTY_TXN are the differential output pairs for each of the transmitters in the GTY transceiver Quad
GTY_REFCLKP, GTY_REFCLKN	Input	Configured as either reference clock input pins or as RX recovered clock output pins for the GTY transceiver Quad
GTY_AVTTRCAL	Input (Pad)	Bias current supply for the termination resistor calibration circuit
GTY_RREF	Input (Pad)	Calibration resistor input pin for the termination resistor calibration circuit
GTY_AVCC	Input (Pad)	GTY_AVCC is the analog supply for the internal analog circuits of the GTY transceiver Quad tile. This includes the analog circuits for the PLLs, transmitters, and receivers. Most packages have multiple groups of power supply connections in the package for GTY_AVCC. Refer to the package pin definitions to identify in which power supply group a specific GTY transceiver Quad is located. The nominal voltage is 0.88V _{DC} .
GTY_AVTT	Input (Pad)	GTY_AVTT is the analog supply for the transmitter and receiver termination circuits of the GTY transceiver Quad tile. Most packages have multiple groups of power supply connections in the package for GTY_AVTT. Refer to the package pin definitions to identify in which power supply group a specific GTY transceiver Quad is located. The nominal voltage is 1.2V _{DC} .
GTY_AVCCAUX	Input (Pad)	GTY_VCCAUX is the analog LCPLL voltage supply for the transceivers. Most packages have multiple groups of power supply connections in the package for GTY_AVCCAUX. Refer to the package pin definitions to identify in which power supply group a specific GTY transceiver Quad is located. The nominal voltage is 1.8V _{DC} .



SYSMON Pin Definitions

Table 8: SYSMON Pin Definitions

Pin Name	Direction	Description
VREFP	N/A	This pin can be tied to an external 1.024V accurate reference IC for best performance of the ADC. This pin should be connected to GND_SMON if an external reference is not supplied.
VREFN	N/A	This pin should be tied to the ground pin of an external 1.024V accurate reference IC for best performance of the ADC. This pin should always be connected to GND_SMON even if an external reference is not supplied.
VP	Input	This is the positive input terminal of the dedicated differential analog input channel (VP/VN). When not used, tie to GND_SMON.
VN	Input	This is the negative input terminal of the dedicated differential analog input channel (VP/VN). When not used, tie to GND_SMON.

Footprint Compatibility between Packages

Versal devices are footprint compatible only with other Versal devices with the same numerical portion of the package name and the same preceding single character alphabetic designator. For example, the VM1802-VSVD1760 is footprint compatible with the VC1902-VSVD1760, because the 1760 is preceded with a D in both package names, but not footprint compatible with the VM1802-VFVC1760. Also, the VC1502-VSVA1596 is footprint compatible with the VC1902-VIVA1596, regardless of a difference in package dimensions, because the 1596 is preceded by an A in both package names. Pins that are available in one device but are not available in another device are labeled as NC in the package file of the other device.



IMPORTANT! Footprint compatibility does not necessarily imply that all pins will function in the same manner for different devices in a package.

The following table shows the footprint compatible devices available for each package. See the *Versal Architecture and Product Data Sheet: Overview* (DS950) for specific package letter code options. All packages are available with eutectic BGA balls. For these packages, the device type is XQ and the Pb-free signifier in the package name is a Q.

Table 9: Footprint Compatibility

Packages		Footpr	int Compatible [Devices
SFVB625	VM1102			
VBVA1024	VC1352	VC1502		
VFVB1024	VM1102	VM1302	VM1402	
VFVB1369	VM1302	VM1402	VM1502	
VSVE1369	VC1352	VC1702		



Table 9: Footprint Compatibility (cont'd)

Packages		Footpr	int Compatible D)evices	
VFVF1369	VM1302	VM1402			
VSVG1369	VC1502				
VSVA1596 VIVA1596 ¹	VC1502	VC1702	VC1802	VC1902	
VFVA1760	VM1302	VM1402	VM2602		
VFVC1760	VM1502	VM1802	VM2602	VM2902	
VSVD1760	VM1802	VC1802	VC1902		
VSVA2197	VM1802	VM2502	VC1502	VC1802	VC1902

Notes:

Many Versal devices that are footprint compatible in a package have different I/O bank and transceiver quad numbers connected to the same package pins. Due to these differences, when migrating between devices in a specific package, the type of bank (HD vs. XP) or quad (GTY, GTYP, or GTM), whether a bank is connected or NC at the package pins, and where the bank or quad is located on the die must be taken into consideration. The following tables show how the banks and transceiver quads are numbered between devices in each package. For all grouped-together footprint-compatible packages, the bank and quad numbers in the same column (indicated by the letters A through Z) for each device are connected to the same package pins. For example, in the VSVA2197 packages, quad 202 for the VM2502 is connected to the same pins as quad 203 for the VM1802, VC1502, VC1802, and VC1902. For a visual representation of all of this information, see Figure 1: Example Device Diagram.

Related Information

I/O Bank Footprint Compatibility between Packages Transceiver Footprint Compatibility between Packages

^{1.} While footprint compatible, the body size for the VIVA1596 is 40 mm x 40 mm, which is larger than the 37.5 mm body size for the VSVA1596 package.



I/O Bank Footprint Compatibility between Packages

Table 10: I/O Bank Migration

Package	Device	А	В	С	D	E	F	G	Н	I	J	К	L	M-U	АА	АВ	AC	AD	AE	AF	AG	АН	AI-AU	Unbonded I/O Banks
SFVB625	VM1102	700	701	702	703										304							Ì	Ì	
VBVA1024	VC1352	700	701	702	703	704	705	706							604									302, 204, 203, 202, 201, 200
VBVA1024	VC1502	700	701	702	703	704	705	706							406									306
VFVB1024	VM1102	700	701	702	703										304									
VFVB1024	VM1302	700	701	702	703										306	307								800, 801, 802, 803, 804, 704, 805, 705
VFVB1024	VM1402	700	701	702	703	704	705								306	307								800, 801, 802, 803, 804, 805
VFVB1369	VM1302	700	701	702	703										306	307								800, 801, 802, 803, 804, 704, 805, 705
VFVB1369	VM1502	700	701	702	703	704	705	706							406	306								
VFVB1369	VM1402	700	701	702		703	704	705							306	307								800, 801, 802, 803, 804, 805
VSVE1369	VC1352	700	701	702	703	704	705	706							604	302								204, 203, 202, 201, 200
VSVE1369	VC1702	700	701	702	703	704	705	706							608	302								208, 207, 206, 205, 204, 203, 202, 201, 200
VIVA1596	VC1802	700	701	702	703	706	707	708							406	306								704, 705, 709, 710, 711



Table 10: I/O Bank Migration (cont'd)

Package	Device	А	В	С	D	E	F	G	Н	I	J	К	L	M-U	AA	АВ	AC	AD	AE	AF	AG	АН	AI-AU	Unbonded I/O Banks
VIVA1596	VC1902	700	701	702	703	706	707	708							406	306								704, 705, 709, 710, 711
VSVA1596	VC1502	700	701	702	703	704	705	706							406	306								
VSVA1596	VC1702	700	701	702	703	704	705	706							608	302								208, 207, 206, 205, 204, 203, 202, 201, 200
VFVA1760	VM1302	700	701	702	703										800	801	802	803			307	306		804, 704, 805, 705
VFVA1760	VM1402	700	701	702	703	704	705								800	801	802	803	804	805	307	306		
VFVA1760	VM2602	700	701	702	703	704	705	706	707						800	801	802	803	804	805				806, 807, 808, 708
VFVC1760	VM1502	700	701	702											704	705	706	703	306	406				
VFVC1760	VM1802	700	701	702											703	704	705	706	306	406				707, 708, 709, 710, 711
VFVC1760	VM2602	700	701	702											703	704	705	706						800, 801, 802, 803, 804, 805, 806, 807, 707, 808, 708
VFVC1760	VM2902	700	701	702											703	704	705	706		412				800, 801, 802, 803, 804, 805, 806, 807, 707, 808, 708
VSVD1760	VM1802	700	701	702	703	704	705	706	707	708	709	710	711											306, 406
VSVD1760	VC1802	700	701	702	703	704	705	706	707	708	709	710	711											306, 406
VSVD1760	VC1902	700	701	702	703	704	705	706	707	708	709	710	711											306, 406
VSVA2197	VM2502	700	701	702	703	704	705	706	707	708	709	710	711			406								712



Table 10: I/O Bank Migration (cont'd)

Package	Device	Α	В	С	D	E	F	G	н	I	J	К	L	M-U	AA	АВ	AC	AD	AE	AF	AG	АН	AI-AU	Unbonded I/O Banks
VSVA2197	VM1802	700	701	702	703	704	705	706	707	708	709	710	711		306	406								
VSVA2197	VC1502	700	701	702	703			704	705	706					306	406								
VSVA2197	VC1802	700	701	702	703	704	705	706	707	708	709	710	711		306	406								
VSVA2197	VC1902	700	701	702	703	704	705	706	707	708	709	710	711		306	406								



Transceiver Footprint Compatibility between Packages

Table 11: Transceiver Migration - Left Side (GTM Quads are Shaded)

Package	Device	CA	СВ	СС	CD	CE	CF	CG	СН	CI	CJ	СК	CL	СМ	CN	со	СР	CQ
SFVB625	XCVM1102	L			î		ĺ	î			ì	ĺ					ı	î
		103																
VBVA1024	XCVC1352	L	L															
		103	104															
VBVA1024	XCVC1502	L	L															
		103	104															
VFVB1024	XCVM1102	L	L	L														
		102	103	104														
VFVB1024	XCVM1302	L	L	L	L													
		102	103	104	105													
VFVB1024	XCVM1402	L	L	L	L													
		102	103	104	105													
VFVB1369	XCVM1302	LS	LS	LS	LS		LN	LN										
		102	103	104	105		106	107										
VFVB1369	XCVM1502	LS	LS	LS	LS		-	-	-									
		103	104	105	106													
VFVB1369	XCVM1402	LS	LS	LS	LS		LN	LN										
		102	103	104	105		106	107										
VSVE1369	XCVC1352	L	L															
		103	104															
VSVE1369	XCVC1702	L	L	L	L	L	L											
		103	104	105	106	107	108											
VIVA1596	XCVC1802	L	L	L	L													
		103	104	105	106													
VIVA1596	XCVC1902	L	L	L	L													
		103	104	105	106													



Table 11: Transceiver Migration – Left Side (GTM Quads are Shaded) (cont'd)

Package	Device	CA	СВ	СС	CD	CE	CF	CG	СН	CI	CJ	СК	CL	СМ	CN	со	СР	CQ
VSVA1596	XCVC1502	L	L	L	L													
		103	104	105	106													
VSVA1596	XCVC1702	L	L	L	L													
		103	104	105	106													
VFVA1760	XCVM1302	L	L	L	L	┙	L											
		102	103	104	105	106	107											
VFVA1760	XCVM1402	L	L	L	L	٦	L											
		102	103	104	105	106	107											
VFVA1760	XCVM2602	L	L	L	L	٦	L											
		102	103	104	105	106	107											
VFVC1760	XCVM1502	L	L	L	L													
		103	104	105	106													
VFVC1760	XCVM1802	L	L	L	L													
		103	104	105	106													
VFVC1760	XCVM2602	L	L	L	L	L	L											
		102	103	104	105	106	107											
VFVC1760	XCVM2902	L	L	L	L	L	L											
		102	103	104	105	106	107											
VSVD1760	XCVM1802	L	L	L	L		-											
		103	104	105	106													
VSVD1760	XCVC1802	L	L	L	L													
		103	104	105	106													
VSVD1760	XCVC1902	L	L	L	L													
		103	104	105	106													
VSVA2197	XCVM2502	L	L	L	L													
		102	103	104	105													
VSVA2197	XCVM1802	L	L	L	L													
		103	104	105	106													



Table 11: Transceiver Migration – Left Side (GTM Quads are Shaded) (cont'd)

Package	Device	CA	СВ	СС	CD	CE	CF	CG	СН	CI	CJ	СК	CL	СМ	CN	со	СР	cq
VSVA2197	XCVC1502	L	L	L	L													
		103	104	105	106													
VSVA2197	XCVC1802	L	L	L	L													
		103	104	105	106													
VSVA2197	XCVC1902	L	L	L	L													
		103	104	105	106													



Table 12: Transceiver Migration – Right Side (GTM Duals are Shaded)

Package	Device	ВА	ВВ	ВС	BD	BE	BF	BG	ВН	BI	BJ	ВК	BL	ВМ	BN	во	BP	ВQ	BR	BS	ВТ	BU	BV	BW	вх	BY
SFVB625	XCVM1102																								-	
VBVA1024	XCVC1352																									
VBVA1024	XCVC1502																									
VFVB1024	XCVM1102																									
VFVB1024	XCVM1302																									
VFVB1024	XCVM1402																									
VFVB1369	XCVM1302																									
VFVB1369	XCVM1502																									
VFVB1369	XCVM1402																									
VSVE1369	XCVC1352																									
VSVE1369	XCVC1702																									
VIVA1596	XCVC1802	R	R	R	R																					
		202	203	204	205																					
VIVA1596	XCVC1902	R	R	R	R																					
		202	203	204	205																					
VSVA1596	XCVC1502	R	R	R	R																					
		202	203	204	205																					
VSVA1596	XCVC1702																									
VFVA1760	XCVM1302																									
VFVA1760	XCVM1402																									
VFVA1760	XCVM2602																									
VFVC1760	XCVM1502	RS	RS	RS	RS	RN	RN	RN																		
		200	201	202	203	204	205	206																		
VFVC1760	XCVM1802	RS	RS	RS	RS	RN	RN	RN																		
		200	201	202	203	204	205	206																		
VFVC1760	XCVM2602	RS	RS	RS	RS	RN	RN	RN	RN																	
		200	201	202	203	204	205	206	207																	
VFVC1760	XCVM2902	RS	RS	RS	RS	RN	RN	RN	RN																	
		200	201	202	203	204	205	206	207																	



Table 12: Transceiver Migration - Right Side (GTM Duals are Shaded) (cont'd)

Package	Device	ВА	ВВ	вс	BD	BE	BF	BG	вн	ВІ	BJ	вк	BL	ВМ	BN	во	ВР	ВQ	BR	BS	ВТ	BU	BV	BW	вх	BY
VSVD1760	XCVM1802	R	R																							
		203	204	1																						
VSVD1760	XCVC1802	R	R																							
		203	204																							
VSVD1760	XCVC1902	R	R																							
		203	204																							
VSVA2197	XCVM2502			_	R	R	R	R																		
					202	203	204	205																		
VSVA2197	XCVM1802	R	R	R	R	R	R	R																		
		200	201	202	203	204	205	206																		
VSVA2197	XCVC1502	R	R	R	R	R	R	R																		
		200	201	202	203	204	205	206																		
VSVA2197	XCVC1802	R	R	R	R	R	R	R																		
		200	201	202	203	204	205	206																		
VSVA2197	XCVC1902	R	R	R	R	R	R	R																		
		200	201	202	203	204	205	206																		



Table 13: **Transceiver Migration – Unbonded Banks**

Package	Device	Unbonded Banks
SFVB625	XCVM1102	104, 102
VBVA1024	XCVC1352	
VBVA1024	XCVC1502	106, 105, 206, 205, 204, 203, 202, 201, 200
VFVB1024	XCVM1102	
VFVB1024	XCVM1302	107, 106
VFVB1024	XCVM1402	107, 106
VFVB1369	XCVM1302	
VFVB1369	XCVM1502	206, 205, 204, 203, 202, 201, 200
VFVB1369	XCVM1402	
VSVE1369	XCVC1352	
VSVE1369	XCVC1702	
VIVA1596	XCVC1802	206, 201, 200
VIVA1596	XCVC1902	206, 201, 200
VSVA1596	XCVC1502	206, 201, 200
VSVA1596	XCVC1702	108, 107
VFVA1760	XCVM1302	
VFVA1760	XCVM1402	
VFVA1760	XCVM2602	207, 206, 205, 204, 203, 202, 201, 200
VFVC1760	XCVM1502	
VFVC1760	XCVM1802	
VFVC1760	XCVM2602	
VFVC1760	XCVM2902	112, 111, 110, 109, 108, 212, 211, 210, 209, 208
VSVD1760	XCVM1802	206, 205, 202, 201, 200
VSVD1760	XCVC1802	206, 205, 202, 201, 200
VSVD1760	XCVC1902	206, 205, 202, 201, 200
VSVA2197	XCVM2502	106, 206, 201, 200
VSVA2197	XCVM1802	



Table 13: Transceiver Migration - Unbonded Banks (cont'd)

Package	Device	Unbonded Banks
VSVA2197	XCVC1502	
VSVA2197	XCVC1902	





Die Level Bank Numbering and Device Diagrams

Die Level Bank Numbering Overview

Banking and Clocking Summary

For each device, not all banks are bonded out in every package.

GTY and GTM Columns

- One GT Quad = Four transceivers = Four GTYE5 QUAD or GTME5 QUAD primitives.
- Not all GT Quads are bonded out in every package.
- Also shown are quads labeled with RCAL. This specifies the location of the RCAL masters for each device. With respect to the package, the RCAL masters are located on the same package pin for each package, regardless of the device.
- The XY coordinates shown in each quad correspond to the transceiver channel number found in the pin names for that quad (as shown in the next section).
- An alphabetic designator is shown in each quad. Each letter corresponds to the columns in the tables in the Transceiver Footprint Compatibility between Packages section.
- The power supply group is shown in brackets [] for each quad.

I/O Banks

- Each user XPIO bank has a total of 54 I/Os that can be used as differential (27 differential pairs) or single-ended I/Os. All 54 pads of a bank are not always bonded out to pins.
- A limited number of XPIO banks have fewer than 54 SelectIO pins. These banks are labeled as partial.
- Each user HDIO bank has a total of 22 I/Os that can be used as pseudo-differential (11 differential pairs) or single-ended I/Os.
- Adjacent to each bank is a physical layer (PHY) containing clock buffers and clock management resources



- XPIO banks are arranged in rows on the north and south of the device with adjacent PHY and clock management resources.
- XPIO banks are separated into groups of 1, 2, or 3 banks that signify how to group them when used for DDR memory controller applications.
- I/Os in some banks on the left and right edges of the XPIO rows do not have direct access to all I/O logic resources and can only be used for DDR memory controller (DDRMC) applications. These I/Os are specified in the following device diagrams, where each XPIO bank is designated by a Y (DDRMC only) or a N (access to all I/O logic resources) for each nibble (nine nibbles per bank and six I/Os per nibble). This is also specified in the DDRMC Only column of the Chapter 3: Package Files.
- Global clock (GC) pins in DDRMC Only nibbles include full access to clock management resources.
- HDIO banks are arranged in columns and separated into rows that are pitch-matched with adjacent PHY, clock management resources, and GT blocks.
- An alphabetic designator is shown in each bank. Each letter corresponds to the columns in Table 10.

Clocking

- Each XPIO bank has four pairs of global clock (GC) inputs for four differential or four singleended clock inputs. Single-ended clock inputs should be connected to the P-side of the differential pair.
- Each HDIO bank has two global clock (HDGC) inputs for two single-ended clock inputs, a pseudo-differential pair or a true-differential pair for a limited selection of I/O standards.
- Clock signals are distributed through global buffers driving routing and distribution networks to reach any clock region, I/O, or GTY transceivers.
- Global clock inputs can connect to MMCMs and PLLs within the XPIO bank or adjacent clock management resources

Processor Blocks

- PMC MIO pins are in banks 500 and 501
- LPD MIO pins are in bank 502
- PMC dedicated pins are in bank 503

PCIe, CPM, Interlaken, and 100GE Integrated Blocks

- PCIe: Integrated block for PCIe®. The PCIe blocks with an additional (Tandem) label support tandem configuration.
- CPM: CCIX and PCIe® processor sub-system module
- ILKN: Interlaken block



• MRMAC: 100G Ethernet block



Device Diagrams Overview

The following figure shows an example diagram with a brief explanation for each component.

HDIO GTY Quad 206 GTY Ouad 106 Bank 306 X0Y6 Bank 406 BG [R] CD [L] AB AA GTY Quad 205 GTY Quad 105 PCIE PCIE X0Y5 X1Y5 X0Y2 X1Y2 CC [L] (RCAL) BF [R] GTY Quad 104 GTY Quad 204 MRMAC PCIE X0Y1 X0Y3 CB [L] (RCAL) BE [R] GTY Quad 103 GTY Quad 203 MRMAC **X0Y3** CPM4 X0Y2 BD [R] (RCAL) CA [L] GTY Quad 202 PCIE CPM4 CPM4 X1Y0 BC [R] (RCAL) GTY Quad 201 **LPDMIO PMCDIO** MRMAC Transceiver Power Bank 502 Bank 503 X0Y1 BB [R]◀ Supply Group GTY Quad 200 PMCMIO/PMCDIO PMCMIO MRMAC X1Y0 Bank 500 Bank 501 X0Y0 -BA [R] Bank Type **XPIO XPIO XPIO XPIO XPIO XPIO XPIO XPIO** xbio **XPIO** XPIO-XPIO Bank 700 Bank 701 Bank 703 Bank 704 Bank 706 Bank 707 Bank 709 Bank 710 Bank 702 Bank 705 Bank 708 Bank 71 В D G Н DDRMC Only YYYYYYYY YYYYYYYY имимимим имимимими ииииииии ииииииии ииииииии иииииииии YYYYYYYY XPIO has access to DDRMC only (Y) Alphabetic Bank/Quad Designator. XPIO Bank Integrated Blocks or full access to I/O logic resources (N), Corresponds to Columns in I/O Bank Triplet and Transceiver as shown for each nibble and Transceiver Migration tables. XY Coordinates Boundary (9 nibbles per bank and 6 I/Os per nibble)

Figure 1: Example Device Diagram

X22651-071320

The figures in this chapter show a die view of each device followed by a view with respect to each available package. The available resources by device and package are detailed in the *Versal Architecture and Product Data Sheet*: Overview (DS950).



VC1802 Bank Diagram Overview

Figure 2: VC1802 Banks

GTY Quad 106	HDIO	HDIO	GTY Quad 206
X0Y6	Bank 306	Bank 406	X1Y6
GTY Quad 105 X0Y5 (RCAL)	PCIE X0Y2	PCIE X1Y2	GTY Quad 205 X1Y5
GTY Quad 104 X0Y4 (RCAL)	PCIE X0Y1	MRMAC X0Y3	GTY Quad 204 X1Y4
GTY Quad 103 X0Y3	CPM4	MRMAC X0Y2	GTY Quad 203 X1Y3 (RCAL)
CPM4	CPM4	PCIE X1Y0	GTY Quad 202 X1Y2 (RCAL)
LPDMIO	PMCDIO	MRMAC	GTY Quad 201
Bank 502	Bank 503	X0Y1	X1Y1
PMCMIO/PMCDIO	PMCMIO	MRMAC	GTY Quad 200
Bank 500	Bank 501	X0Y0	X1Y0
XPIO XPIO XPIO	XPIO XPIO XPIO	XPIO XPIO XPIO	XPIO XPIO XPIO
Bank 700 Bank 701 Bank 702	Bank 703 Bank 704 Bank 705	Bank 706 Bank 707 Bank 708	Bank 709 Bank 710 Bank 711

DDRMC Only (by nibble):

X24037-052420



Bank Diagram by Package for VC1802

Figure 3: VC1802 Banks in VIVA1596 Package

	G ⁻	TY Quad 1 X0Y6 CD [L]	06		HDIO Bank 306 AB			HDIO Bank 406 AA		G	TY Quad 20 X1Y6	06	
		TY Quad 1 X0Y5 C [L] (RCA			PCIE X0Y2			PCIE X1Y2		G	TY Quad 20 X1Y5 BD [R]	05	
		TY Quad 1 X0Y4 B [L] (RCA			PCIE X0Y1			MRMAC X0Y3		G	04		
	G ⁻	TY Quad 1 X0Y3 CA [L]	03		CPM4			MRMAC X0Y2			203 L)		
		CPM4			CPM4			PCIE X1Y0		GTY Quad 202 X1Y2 BA [R] (RCAL)			
		LPDMIO Bank 502			PMCDIO Bank 503			MRMAC X0Y1		GTY Quad 201 X1Y1			
		CMIO/PMC Bank 500	OIO		PMCMIO Bank 501			MRMAC X0Y0		G	TY Quad 20 X1Y0	00	
	XPIO Bank 700 A	XPIO Bank 701 B	XPIO Bank 702 C	XPIO Bank 703 D	XPIO Bank 704	XPIO Bank 705	XPIO Bank 706 E	XPIO Bank 707 F	XPIO Bank 708 G	XPIO Bank 709	XPIO Bank 710	XPIO Bank 711	
DDRMC Only (by nibble):	YYYYYYYY	YYYYYYYY	YYYYNNNNN	иииииииии	ииииииии	ииииииии	иииииииии	иииииииии	имимимими	ииииииии	ииииииии	YYYYYYYY	

X24036-052420

Figure 4: VC1802 Banks in VSVD1760 Package

	G1	TY Quad 10 X0Y6 CD [L]	06	HDIO Bank 306				HDIO Bank 406		G ⁻	06		
		TY Quad 10 X0Y5 C [L] (RCAL			PCIE X0Y2			PCIE X1Y2		G ⁻	TY Quad 20 X1Y5	05	
		TY Quad 10 X0Y4 B [L] (RCAI			PCIE X0Y1			MRMAC X0Y3		G ⁻)4		
	G ⁻	TY Quad 10 X0Y3 CA [L]	03		CPM4			MRMAC X0Y2		GTY Quad 203 X1Y3 BA [R] (RCAL)			
		СРМ4			СРМ4			PCIE X1Y0		GTY Quad 202 X1Y2 (RCAL)			
	LPDMIO Bank 502 PMCMIO/PMCDIO Bank 500				PMCDIO Bank 503			MRMAC X0Y1		GTY Quad 201 X1Y1			
				PMCMIO Bank 501			MRMAC X0Y0			GTY Quad 200 X1Y0			
	XPIO	XPIO	XPIO	XPIO	XPIO	XPIO	XPIO	XPIO	XPIO	XPIO	XPIO	XPIO	
	Bank 700 A	Bank 701 B	Bank 702 C	Bank 703 D	Bank 704 E	Bank 705 F	Bank 706 G	Bank 707 H	Bank 708	Bank 709 J	Bank 710 K	Bank 711 L	
DDRMC Only (by nibble):	YYYYYYYY	YYYYYYYY	YYYYNNNNN	ииииииии	ииииииии	иииииииии	ииииииии	иииииииии	ииииииии	иииииииии	иииииииии	YYYYYYYY	

X24038-052420



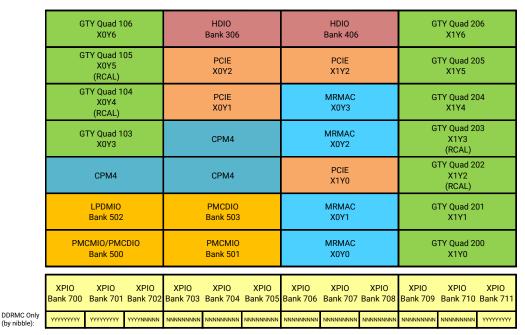
GTY Quad 106 GTY Quad 206 **HDIO HDIO** Bank 306 Bank 406 BG [R] CD [L] AAAB GTY Quad 105 GTY Quad 205 PCIF PCIF X0Y5 X0Y2 X1Y2 CC [L] (RCAL) BF [R] GTY Quad 104 GTY Quad 204 PCIE MRMAC X0Y4 X0Y3 CB [L] (RCAL) GTY Quad 103 GTY Quad 203 MRMAC X0Y3 CPM4 X0Y2 CA [L] BD [R] (RCAL) GTY Quad 202 PCIE CPM4 CPM4 X1Y0 BC [R] (RCAL) GTY Ouad 201 LPDMIO MRMAC Bank 502 Bank 503 X0Y1 BB [R] GTY Quad 200 PMCMIO/PMCDIO **PMCMIO** MRMAC Bank 500 Bank 501 X0Y0 BA [R] XPI0 XPI0 **XPIO** XPI0 XPI0 XPI0 XPIO XPI0 XPI0 Bank 700 Bank 701 Bank 702 Bank 703 Bank 704 Bank 705 Bank 706 Bank 707 Bank 708 Bank 709 Bank 710 Bank 711 D G Н YYYYNNNNN имимимим имимимими YYYYYYYY YYYYYYYY ииииииии иииииииии NNNNNNN иииииииии имимимим имимимими YYYYYYYY (by nibble):

Figure 5: VC1802 Banks in VSVA2197 Package

X24039-052420

VC1902 Bank Diagram Overview

Figure 6: VC1902 Banks



X24015-052420



Bank Diagram by Package for VC1902

Figure 7: VC1902 Banks in VIVA1596 Package

G	TY Quad 106 X0Y6 CD [L]			HDIO Bank 306 AB			HDIO Bank 406 AA		GTY Quad 206 X1Y6			
	TY Quad 105 X0Y5 CC [L] (RCAL)			PCIE X0Y2			PCIE X1Y2		G	TY Quad 20 X1Y5 BD [R]	05	
	TY Quad 104 X0Y4 B [L] (RCAL)			PCIE X0Y1			MRMAC X0Y3		GTY Quad 204 X1Y4 BC [R]			
G	TY Quad 103 X0Y3 CA [L]			CPM4			MRMAC X0Y2		GTY Quad 203 X1Y3 BB [R] (RCAL)			
	CPM4			CPM4			PCIE X1Y0		GTY Quad 202 X1Y2 BA [R] (RCAL)			
	LPDMIO Bank 502			PMCDIO Bank 503		MRMAC X0Y1			GTY Quad 201 X1Y1			
РМ	CMIO/PMCDIO Bank 500)		PMCMIO Bank 501			MRMAC X0Y0		G`	TY Quad 20 X1Y0	00	
Α	XPIO X Bank 701 Bar B	(PIO nk 702 C	XPIO Bank 703 D	XPIO Bank 704	XPIO Bank 705	XPIO Bank 706 E	XPIO Bank 707 F	XPIO Bank 708 G	XPIO Bank 709	XPIO Bank 710	XPIO Bank 711	
DDRMC Only (by nibble):	YYYYYYYY YYY	YNNNNN	иииииииии	ииииииии	ииииииии	ииииииии	ииииииии	ииииииии	ииииииии	ииииииии	YYYYYYYY	

X24016-052020

Figure 8: VC1902 Banks in VSVD1760 Package

	GT	TY Quad 10 X0Y6 CD [L])6		HDIO Bank 306			HDIO Bank 406		GTY Quad 206 X1Y6			
		TY Quad 10 X0Y5 C [L] (RCAL			PCIE X0Y2			PCIE X1Y2		G ⁻	TY Quad 20 X1Y5)5	
		TY Quad 10 X0Y4 B [L] (RCAL			PCIE X0Y1			MRMAC X0Y3		GTY Quad 204 X1Y4 BB [R]			
	G1	TY Quad 10 X0Y3 CA [L])3		CPM4			MRMAC X0Y2		GTY Quad 203 X1Y3 BA [R] (RCAL)			
		СРМ4			CPM4			PCIE X1Y0		GTY Quad 202 X1Y2 (RCAL)			
		LPDMIO Bank 502			PMCDIO Bank 503			MRMAC X0Y1		GTY Quad 201 X1Y1			
	PMCMIO/PMCDIO Bank 500			PMCMIO Bank 501			MRMAC X0Y0			GTY Quad 200 X1Y0			
	XPIO Bank 700 A	XPIO Bank 701 B	XPIO Bank 702 C	XPIO Bank 703 D	XPIO Bank 704 E	XPIO Bank 705 F	XPIO Bank 706 G	XPIO Bank 707 H	XPIO Bank 708	XPIO Bank 709 J	XPIO Bank 710 K	XPIO Bank 711 L	
DDRMC Only (by nibble):	YYYYYYYY	YYYYYYYY	YYYYNNNNN	ииииииии	иииииииии	иииииииии	ииииииии	иииииииии	иииииииии	иииииииии	иииииииии	YYYYYYYY	

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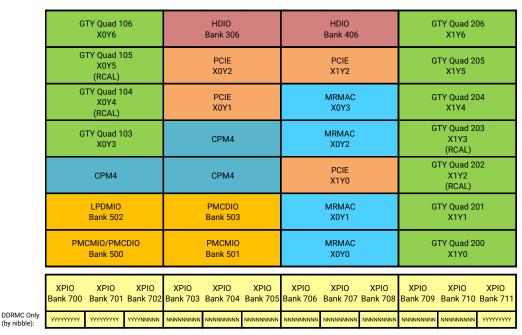
GTY Quad 106 GTY Quad 206 **HDIO HDIO** Bank 306 Bank 406 BG [R] CD [L] AAAB GTY Quad 105 GTY Quad 205 PCIF PCIF X0Y5 X0Y2 X1Y2 CC [L] (RCAL) BF [R] GTY Quad 104 GTY Quad 204 PCIE MRMAC X0Y4 X0Y3 CB [L] (RCAL) GTY Quad 103 GTY Quad 203 MRMAC X0Y3 CPM4 X0Y2 CA [L] BD [R] (RCAL) GTY Quad 202 PCIE CPM4 CPM4 X1Y0 BC [R] (RCAL) GTY Ouad 201 **LPDMIO** MRMAC Bank 502 Bank 503 X0Y1 BB [R] GTY Quad 200 PMCMIO/PMCDIO **PMCMIO** MRMAC Bank 500 Bank 501 X0Y0 BA [R] XPI0 XPI0 **XPIO** XPI0 XPI0 XPI0 XPIO XPI0 XPI0 Bank 700 Bank 701 Bank 702 Bank 703 Bank 704 Bank 705 Bank 706 Bank 707 Bank 708 Bank 709 Bank 710 Bank 711 D G Н YYYYNNNNN имимимим имимимими YYYYYYYY YYYYYYYY ииииииии иииииииии NNNNNNN иииииииии имимимим имимимими YYYYYYYY

Figure 9: VC1902 Banks in VSVA2197 Package

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VM1802 Bank Diagram Overview

Figure 10: VM1802 Banks



X24040-052420

(by nibble):



Bank Diagram by Package for VM1802

Figure 11: VM1802 Banks in VFVC1760 Package

	G ⁻	TY Quad 10 X0Y6 CD [LS])6	HDIO Bank 306 AE			HDIO Bank 406 AF			G ⁻	TY Quad 20 X1Y6 BG [RN]	06
		GTY Quad 105 X0Y5 CC [LS] (RCAL)			PCIE X0Y2			PCIE X1Y2		G ⁻	TY Quad 20 X1Y5 BF [RN]	05
		TY Quad 10 X0Y4 3 [LS] (RCA			PCIE X0Y1		MRMAC X0Y3		G ⁻	TY Quad 20 X1Y4 BE [RN]	04	
	G⁻	TY Quad 10 X0Y3 CA [LS])3		CPM4			MRMAC X0Y2			TY Quad 20 X1Y3 [RS] (RCA	
		CPM4			CPM4			PCIE X1Y0			TY Quad 20 X1Y2 [RS] (RCA	
		LPDMIO Bank 502			PMCDIO Bank 503			MRMAC X0Y1		G ⁻	TY Quad 20 X1Y1 BB [RS]	01
	PM	CMIO/PMC Bank 500	:DIO		PMCMIO Bank 501			MRMAC X0Y0		G ⁻	ΓY Quad 20 X1Y0 BA [RS]	00
	XPIO Bank 700 A	XPIO Bank 701 B	XPIO Bank 702 C	XPIO Bank 703 AA	XPIO Bank 704 AB	XPIO Bank 705 AC	XPIO Bank 706 AD	XPIO Bank 707	XPIO Bank 708	XPIO Bank 709	XPIO Bank 710	XPIO Bank 711
DDRMC Only (by nibble):	YYYYYYYY	YYYYYYYY	YYYYNNNNN	ииииииии	имимимими	NNNNNNNN	NNNNNNNN	NNNNNNNN	ииииииии	NNNNNNNN	NNNNNNNN	YYYYYYYY

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Figure 12: VM1802 Banks in VSVD1760 Package

GTY Quad 106 X0Y6 CD [L]	HDIO Bank 306	HDIO Bank 406	GTY Quad 206 X1Y6
GTY Quad 105 X0Y5 CC [L] (RCAL)	PCIE X0Y2	PCIE X1Y2	GTY Quad 205 X1Y5
GTY Quad 104 X0Y4 CB [L] (RCAL)	PCIE X0Y1	MRMAC X0Y3	GTY Quad 204 X1Y4 BB [R]
GTY Quad 103 X0Y3 CA [L]	CPM4	MRMAC X0Y2	GTY Quad 203 X1Y3 BA [R] (RCAL)
CPM4	CPM4	PCIE X1Y0	GTY Quad 202 X1Y2 (RCAL)
LPDMIO Bank 502	PMCDIO Bank 503	MRMAC X0Y1	GTY Quad 201 X1Y1
PMCMIO/PMCDIO Bank 500	PMCMIO Bank 501	MRMAC X0Y0	GTY Quad 200 X1Y0
XPIO XPIO XPIO	XPIO XPIO XPIO	XPIO XPIO XPIO	XPIO XPIO XPIO
Bank 700 Bank 701 Bank 702 A B C	Bank 703 Bank 704 Bank 705 D E F	Bank 706 Bank 707 Bank 708 G H I	Bank 709 Bank 710 Bank 711 J K L
THE THEORY OF THE THE THEORY OF THE THEORY O	имининии имининии	имимими имимими имимимими	NNNNNNNN NNNNNNNNN YYYYYYYY

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DDRMC On



Figure 13: VM1802 Banks in VSVA2197 Package

	G ⁻	TY Quad 10 X0Y6 CD [L]	06	HDIO Bank 306 AA			HDIO Bank 406 AB		GTY Quad 206 X1Y6 BG [R]		06	
		TY Quad 10 X0Y5 C [L] (RCAI			PCIE X0Y2			PCIE X1Y2		G [*]	TY Quad 20 X1Y5 BF [R])5
		TY Quad 10 X0Y4 B [L] (RCAI			PCIE X0Y1			MRMAC X0Y3		G`	TY Quad 20 X1Y4 BE [R])4
	G ⁻	TY Quad 10 X0Y3 CA [L]	03		CPM4			MRMAC X0Y2			TY Quad 20 X1Y3 D [R] (RCAI	
		CPM4			CPM4			PCIE X1Y0			TY Quad 20 X1Y2 C [R] (RCAI	
		LPDMIO Bank 502			PMCDIO Bank 503			MRMAC X0Y1		G	TY Quad 20 X1Y1 BB [R])1
	PMO	CMIO/PMC Bank 500	DIO		PMCMIO Bank 501			MRMAC X0Y0		G [*]	TY Quad 20 X1Y0 BA [R]	00
	XPIO Bank 700 A	XPIO Bank 701 B	XPIO Bank 702 C	XPIO Bank 703 D	XPIO Bank 704 E	XPIO Bank 705 F	XPIO Bank 706 G	XPIO Bank 707 H	XPIO Bank 708	XPIO Bank 709 J	XPIO Bank 710 K	XPIO Bank 711 L
nly :	YYYYYYYY	YYYYYYYY	YYYYNNNNN	ииииииии	иииииииии	иииииииии	ииииииии	иииииииии	ииииииии	иииииииии	иииииииии	YYYYYYYY

DDRMC Only (by nibble):

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Package Files

About ASCII Package Files

The ASCII package files for each Versal[™] ACAP include a comma-separated-values (CSV) version and a text version optimized for a browser or text editor in fixed-width fonts. The information in each of the files includes:

- Header with device/package name (family-device-package), date and time of creation, package specification designator, and revision history
- Seven columns containing data for each pin:
 - Pin-Pin location on the package
 - Pin Name—The name of the assigned pin
 - Bank—Bank number
 - I/O Type—HDIO, XPIO, GTY, GTM, PMCMIO, PMCDIO, or LPDMIO depends on the I/O type. For more information on the I/O type, see Versal ACAP SelectIO Resources Architecture Manual (AM010).
 - Super logic region (SLR) number for SSI devices (not applicable for monolithic devices).
 - XPIOPerf—Performance (HIGH, MEDIUM, or LOW) that the LPDDR4 interfaces are specified. See the device data sheet for performance definitions.
 - DDRMC Only—For XPIO pins, YES specifies that the pin is supported for use in DDR applications only and does not include full access to XPIO logic resources. YES_PLUS_GC specifies the pin is supported for use in DDR applications and additionally has full access to clock management resources. NO specifies the pin has full access to XPIO logic resources.
- Total number of pins in the package

Related Information

ASCII Pinout Files



Package Specifications Designations

Package specifications are designated as evaluation only, engineering sample, or production. Each designation is defined as follows.

Evaluation Only

These package specifications are based on initial device specifications, package routability analysis and mechanical package construction. Package specifications with this designation are not stable and package pinouts are likely to change and these specifications should only be used for initial system level design feasibility.

Engineering Sample

These package specifications are based on a released package design and validated with ES engineering sample (ES) devices. Package specifications with this designation are considered stable, however some pinout and mechanical specifications might change prior to the production release of the particular device. Package pinouts with this designation are to be used for PCB and Vivado® designs using ES devices.

Production

These package specifications are released coincident with production release of a particular device. Customers receive formal notification of any subsequent changes.



ASCII Pinout Files

Links to the ASCII pinout information device/package combinations are listed in the following table.

Note: All package files are ASCII files in TXT and CSV file format.



IMPORTANT! IMPORTANT: All packages are available with eutectic BGA balls. To order these packages, the device type starts with an XQ vs. XC or XA, and the Pb-free signifier in the package name is Q.

Table 14: Package/Device Pinout Files

Packages		Footpri	nt Compatible	Devices		Package Status
SFVB625	VM1102					Evaluation Only
VBVA1024	VC1352	VC1502				Evaluation Only
VFVB1024	VM1102	VM1302	VM1402			Evaluation Only
VFVB1369	VM1302	VM1402	VM1502			Evaluation Only
VFVF1369	VM1302	VM1402		•		Evaluation Only
VSVE1369	VC1352	VC1702				Evaluation Only
VSVG1369	VC1502		•			Evaluation Only
VSVA1596	VC1502	VC1702				Evaluation Only
VIVA1596	VC1802	VC1902				Engineering Sample
VFVA1760	VM1302	VM1402	VM2602			Evaluation Only
VFVC1760	VM1502 Evaluation Only	VM1802 Engineering Sample	VM2602 Evaluation Only	VM2902 Evaluation Only		
VSVD1760	VM1802	VC1802	VC1902			Engineering Sample
VSVA2197	VM1802 Engineering Sample	VM2502 Evaluation Only	VC1502 Evaluation Only	VC1802 Engineering Sample	VC1902 Engineering Sample	

Related Information

Package Specifications Designations





Device Diagrams

The diagrams in this chapter show top-view perspective of the package pinout of each Versal™ device/package combination. The following table is a cross reference to the device/package diagrams. The device diagram shows the location of each user I/O, PMCMIO, LPDMIO, PMCDIO, and GTY transceiver and the respective bank or GTY quad, as well as the location of every power pin in the package. See Package Specifications Designations for definitions of Evaluation Only, Engineering Sample, and Production device diagrams.



IMPORTANT! All packages are available with eutectic BGA balls. To order these packages, the device type starts with an XQ vs. XC or XA, and the Pb-free signifier in the package name is Q.

Table 15: Cross-Reference to Versal Device Diagrams by Package

Package		Footpr	rint Compatible D	Devices	
SFVB625	VM1102 Evaluation Only				
VBVA1024	VC1352 Evaluation Only	VC1502 Evaluation Only			
VFVB1024	VM1102 Evaluation Only	VM1302 Evaluation Only	VM1402 Evaluation Only		
VFVF1369	VM1302 Evaluation Only	VM1402 Evaluation Only			
VSVE1369	VC1352 Evaluation Only	VC1702 Evaluation Only			
VSVG1369	VC1502 Evaluation Only				
VSVA1596	VC1502 Evaluation Only	VC1702 Evaluation Only			
VIVA1596	VC1802 Engineering Sample	VC1902 Engineering Sample			
VFVA1760	VM1302 Evaluation Only	VM1402 Evaluation Only	VM2602 Evaluation Only		
VFVC1760	VM1502 Evaluation Only	VM1802 Engineering Sample	VM2602 Evaluation Only	VM2902 Evaluation Only	
VSVD1760	VM1802 Engineering Sample	VC1802 Engineering Sample	VC1902 Engineering Sample		

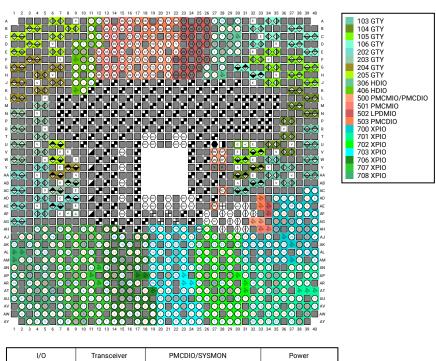


Table 15: Cross-Reference to Versal Device Diagrams by Package (cont'd)

Package	Footprint Compatible Devices					
VSVA2197	VM1802 Engineering Sample	VM2502 Evaluation Only	VC1502 Evaluation Only	VC1802 Engineering Sample	VC1902 Engineering Sample	

VIVA1596 Package—VC1802

Figure 14: VIVA1596 Package—VC1802 Device Diagram



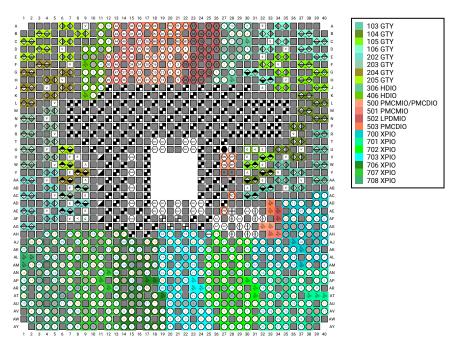
1/0	Transceiver	PMCDIO/SYSMON	Power
○ IO_L#P ○ IO_L#P. ○ IO_L#P.CC ○ IO_L#P.CC ○ IO_L#P.CC ○ IO_L#P.CC ○ IO_VCR ○ IO_VCR ○ IPD_MIO	→ RXP# → RXN# → TXP# → TXN# → TXN# → REFCLKP# → REFCLKN# < AVTTROAL I RREE AVCC V AVTT AVCCAUX		VCCINT VCCAUX VCCAUX VCCAUX VCCLO VCCAUX, PMC VCC.PSLP VCC.PSLP VCC.PSLP VCC.SOC VCC.SOC VCC.SOC VCC.BAT VCC.BATT VCCAUX.SMON GND GND RSVDGND NC CC

X24166-070120



VIVA1596 Package—VC1902

Figure 15: VIVA1596 Package—VC1902 Device Diagram



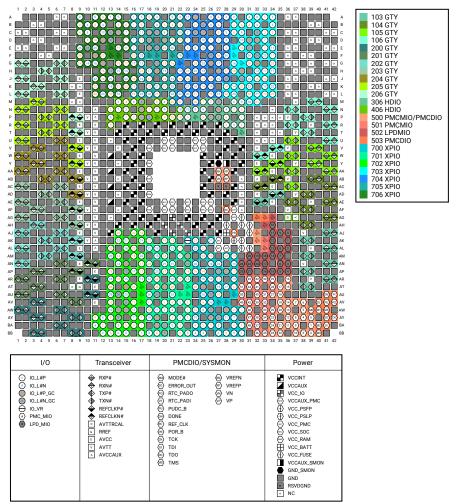
1/0	Transceiver	PMCDIO/SYSMON	Power
IO_L#P O_L#P_GC IO_L#P_GC IO_L#P_GC IO_VR O_PMC_MIO PMC_MIO	→ RXP# → RXP# → TXP# → TXP# → TXP# → TXP# → REFCLKP# → REFCLKP# - AVTTRCAL □ RREF □ AVCC □ AVTT - AVCCAUX		VCCINT VCCAUX VCCAUX VCCAUX VCCAUX VCCAUSFMC VCCASFFP VCCASC VCCAMC VCCA

X24167-070120



VFVC1760 Package—VM1802

Figure 16: VFVC1760 Package—VM1802 Device Diagram

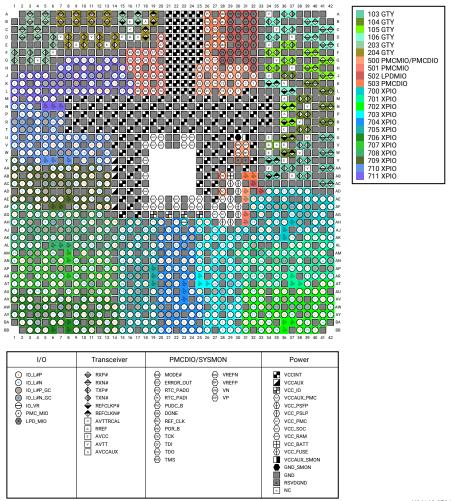


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VSVD1760 Package—VC1802

Figure 17: VSVD1760 Package—VC1802 Device Diagram

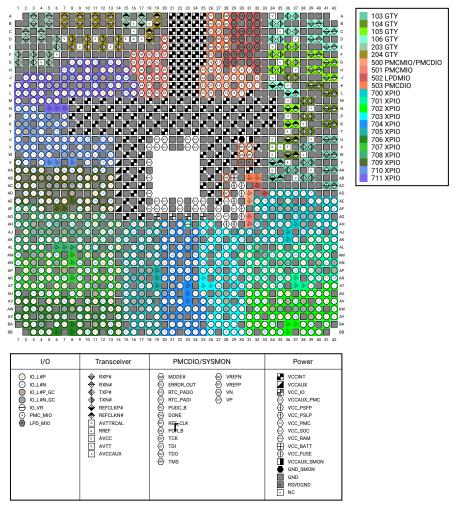


X24168-070120



VSVD1760 Package—VC1902

Figure 18: OLD VSVD1760 Package—VC1902 Device Diagram

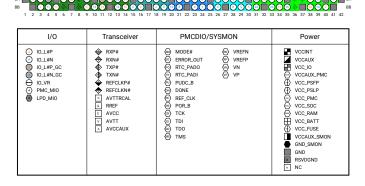


X24170-070120



VSVD1760 Package—VM1802

Figure 19: VSVD1760 Package—VM1802 Device Diagram

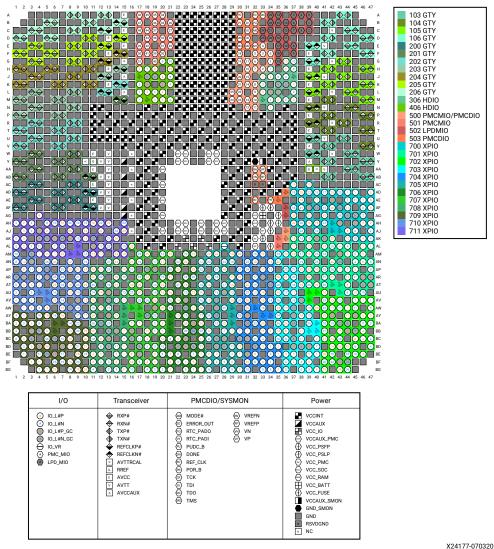


X24175-070320



VSVA2197 Package—VC1802

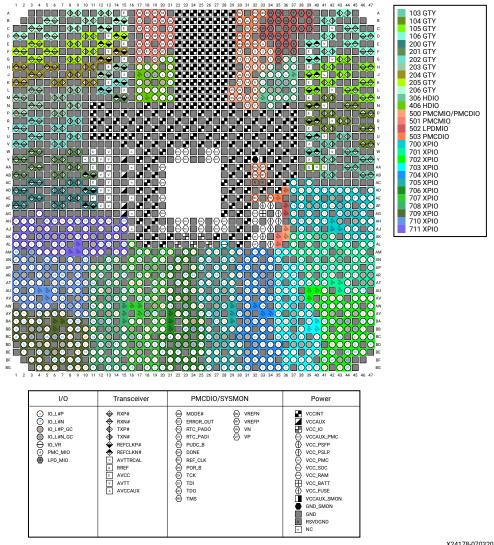
Figure 20: VSVA2197 Package—VC1902 Device Diagram





VSVA2197 Package—VC1902

Figure 21: VSVA2197 Package—VC1902 Device Diagram

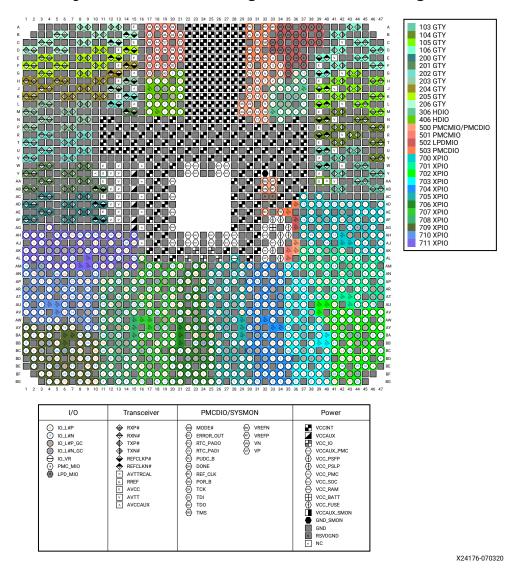


X24178-070320



VSVA2197 Package—VM1802

Figure 22: VSVA2197 Package—VM1802 Device Diagram







Mechanical Drawings

This chapter provides mechanical drawings (package specifications) of the Versal[™] ACAPs. The following table is a cross-reference to the mechanical drawings by device and package combination. See Package Specifications Designations for definitions of Evaluation Only, Engineering Sample, and Production mechanical drawings.



IMPORTANT! All packages are available with eutectic BGA balls. To order these packages, the device type starts with an XQ vs. XC or XA, and the Pb-free signifier in the package name is Q. For the mechanical drawings, refer to the Pb-free version of these packages.

See the Table 18: Mechanical Drawing Dimension Definitions table for details on key dimensions/tolerances shown in each mechanical drawing.

Table 16: Cross-Reference to Versal ACAP AI Core Series Mechanical Drawings by Package

Doelsono			Devices		
Package	VC1352	VC1502	VC1702	VC1802	VC1902
VBVA1024					
VSVE1369					
VSVG1369					
VSVA1596					
VIVA1596				Figure 23 Engineering Sample	Figure 23 Engineering Sample
VSVD1760				Figure 25 Engineering Sample	Figure 25 Engineering Sample
VSVA2197				Figure 26 Engineering Sample	Figure 26 Engineering Sample



Table 17: Cross-Reference to Versal ACAP Prime Series Mechanical Drawings by Package

Da el en en	Devices										
Package	VM1102	VM1302	VM1402	VM1502	VM1802	VM2502	VM2602	VM2902			
SFVB625											
VFVB1024											
VFVB1369											
VFVF1369											
VFVA1760											
VFVC1760					Figure 24 Engineering Sample						
VSVD1760					Figure 25 Engineering Sample						
VSVA2197					Figure 26 Engineering Sample						

Table 18: Mechanical Drawing Dimension Definitions

Dimension	Definition
٥	Bilateral tolerance of package sides with respect to datums A and B
	Flatness tolerance of silicon die or package lid top surface
11	Bilateral tolerance for parallelism of silicon die or package lid top surface with respect to the seating plane datum C
А	Thickness of package with respect to the seating plane datum C
A ₁	Thickness of BGA balls with respect to the seating plane datum C
A ₂	Thickness of package body, including stiffener ring or lid and excluding BGA balls, with respect to the seating plane datum C
A ₃	Distance from top of silicon die to top of stiffener ring or lid with respect to the seating plane datum C
D/E	Length/width of package with respect to datums A and B
D ₁ /E ₁	Length/width of BGA matrix with respect to datums A and B
e	BGA ball pitch measured at the center of each ball
øb	BGA ball diameter
riangle aaa	Unidirectional upward tolerance with respect to the seating plane datum C
/ / bbb	Bilateral tolerance for parallelism of package surface with respect to the seating plane datum C
øddd	BGA ball position tolerance of diameter ddd with respect to datums A and B perpendicular to the seating plane datum C in which the center of each ball must lie
øeee	BGA ball position tolerance of diameter eee measured with respect to other balls within the BGA matrix in which the center of each ball must lie
М	BGA ball matrix size



VIVA1596 Package—VC1802 and VC1902

BOTTOM VIEW □ 0.10 4X В -A \mathbb{D}_1 PIN 1 I.D. 0.20 4.5 3.00 0.40 TYP Ē 4.5 4XØ1.55 -(1.1 DEPTH) 1560X 3X R1.0 -5.80 STIFFENER // bbb C SEATING PLANE e -Øh-Ċ Øeee M C øαααØ C A B VIVA1596 Sn/Ag/Cu SOLDER BALLS MILLIMETERS 0.797 NOM (DIE) N□M. Α 3.60 4.00 0.40 0.50 0.60 CAP - 0.37 MAX HEIGHT 3.10 3.30 3.50 Аз 0.95 1.05 1.15 SECTION A-A D/E 40.00 BASIC NOTES: D1/E1 35.88 BASIC 0.92 BASIC е 1. ALL DIMENSIONS AND TOLERANCES CONFORM Øb 0.50 0.64 TO ASME Y14.5M-1994

2. SYMBOL "M" IS THE PIN MATRIX SIZE.

Figure 23: Package Dimensions for VIVA1596 (VC1802 and VC1902)

X24174-070220

Related Information

aao

bbb

ddd

eee

0.20

0.35

0.25

Mechanical Drawings



VFVC1760 Package—VM1802

BOTTOM VIEW TOP VIEW □ 0.10 4X D A \mathbb{D}_1 В PIN 1 I.D. 0.20 **-**0.20 Ė 4X R0.5 0.45 - | -TYP - 5.80 // bbb C SEATING PLANE e - | aaa C ⊕ øddd∭ CAB øeee∭ C MILLIMETERS MIN. N□M. MAX 3.49 3.69 3.89 Α CAP - 0.37 MAX HEIGHT 0.40 0.50 0.60 SECTION A-A Αa 2.99 3.19 3.39 D/E 40.00 BASIC D1/E1 37.72 BASIC NOTES: 0.92 BASIC е 0.50 0.64 0.70 1. ALL DIMENSIONS AND TOLERANCES CONFORM aao 0.20 TO ASME Y14.5M-1994 bbk 0.35 2. SYMBOL "M" IS THE PIN MATRIX SIZE. ddd 0.25 eee 0.10 42

Figure 24: Package Dimensions for VFVC1760 (VM1802)

Related Information

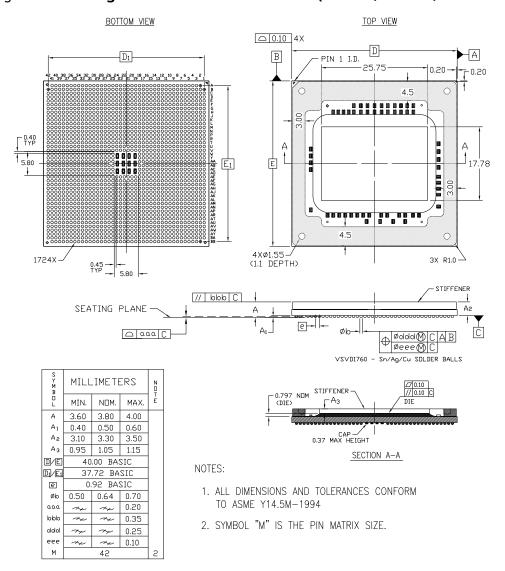
Mechanical Drawings

X24173-070220



VSVD1760 Package—VC1802, VC1902, and VM1802

Figure 25: Package Dimensions for VSVD1760 (VC1802, VC1902, and VM1802)



X24171-070120

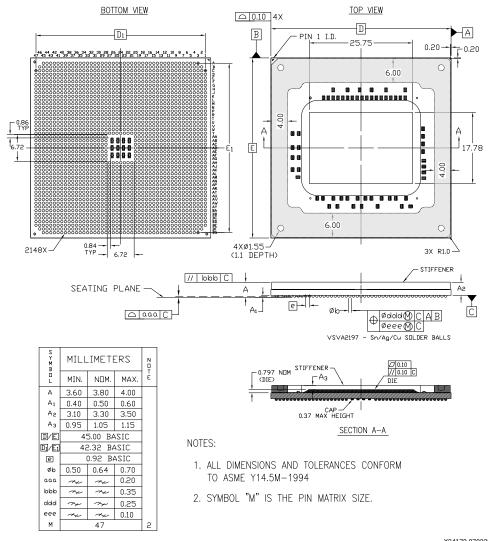
Related Information

Mechanical Drawings



VSVA2197 Package—VC1802, VC1902, and VM1802

Figure 26: Package Dimensions for VSVA2197 (VC1802, VC1902, and VM1802)



X24172-070220

Related Information

Mechanical Drawings





Package Marking

The package top-markings for the XC and XA Versal[™] devices are similar to the examples shown in the following figure.

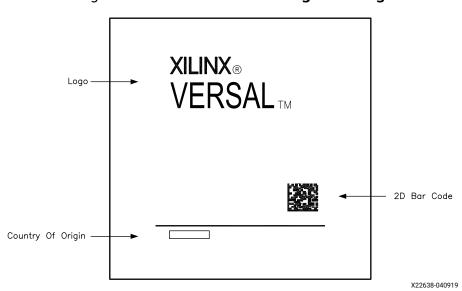


Figure 27: Versal Devices Package Marking

Table 19: Versal Device Marking Definition—Example

Item	Definition
Xilinx Logo	Xilinx logo, Xilinx name with trademark, and trademark-registered status.
Bar Code	A device-specific bar code is marked on each device.





Packing and Shipping

Versal[™] devices are packed in trays. Trays are used to pack most of Xilinx surface-mount devices because they provide excellent protection from mechanical damage. In addition, they are manufactured using antistatic material to provide limited protection against ESD damage and can withstand a bake temperature of 125°C.

Table 20: Standard Device Counts per Tray and Box

Package	Maximum Number of Devices Per Tray	Maximum Number of Units In One Internal Box	
SFVB625	60	300	
VBVA1024			
VFVB1024			
VFVB1369			
VSVE1369			
VSVA1596			
VIVA1596	12	36	
VFVA1760	12	36	
VFVC1760	12	36	
VSVD1760	12	36	
VSVA2197	12	36	



IMPORTANT! All packages are available with eutectic BGA balls. To order these packages, the device type starts with an XQ vs. XC or XA, and the Pb-free signifier in the package name is Q (for example: VSQD1760).





Soldering Guidelines

To implement and control the production of surface-mount assemblies, the dynamics of the solder reflow process and how each element of the process is related to the end result must be thoroughly understood.



RECOMMENDED: Xilinx recommends that customers qualify their custom PCB assembly processes using package samples.

The primary phases of the reflow process are:

- Melting the particles in the solder paste
- Wetting the surfaces to be joined
- Solidifying the solder into a strong metallurgical bond

The peak reflow temperature of a surface-mount component body should not be more than 250°C maximum (260°C for dry rework only) for Pb-free packages and 220°C for eutectic packages, and is package size dependent. For multiple BGAs in a single board and because of surrounding component differences, Xilinx recommends checking all BGA sites for varying temperatures.

The infrared reflow (IR) process is strongly dependent on equipment and loading. Components might overheat due to lack of thermal constraints. Unbalanced loading can lead to significant temperature variation on the board. These guidelines are intended to assist users in avoiding damage to the components; the actual profile should be determined by those using these guidelines. For complete information on package moisture / reflow classification and package reflow conditions, refer to the Joint IPC/JEDEC Standard J-STD-020C.



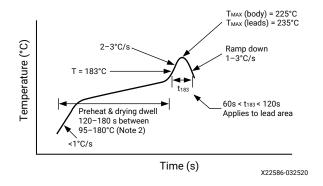
IMPORTANT! Following the initial reflow process, devices should not be reworked more than once. Any additional rework beyond that is likely to cause irreparable damage to the device.



Sn/Pb Reflow Soldering

The following figure shows typical conditions for solder reflow processing of Sn/Pb soldering using IR/convection. Both IR and convection furnaces are used for BGA assembly. The moisture sensitivity of surface-mount components must be verified prior to surface-mount flow.

Figure 28: Typical Conditions for IR Reflow Soldering of Sn/Pb Solder



Notes in figure:

- 1. Maximum temperature range = 225°C (body). Minimum temperature range before 205°C (leads/balls).
- 2. Preheat dwell 95-180°C for 120-180 seconds.
- 3. IR reflow must be performed on dry packages.



Pb-Free Reflow Soldering

Xilinx uses SnAgCu solder balls for commercial-grade (XC) and automotive-grade (XA) BGA packages. In addition, suitable material are qualified for the higher reflow temperatures (250°C maximum, 260°C for dry rework only) required by Pb-free soldering processes.

Xilinx does not support soldering SnAgCu BGA packages with SnPb solder paste using a Sn/Pb soldering process. Traditional Sn/Pb soldering processes have a peak reflow temperature of 220°C. At this temperature range, the SnAgCu BGA solder balls do not properly melt and wet to the soldering surfaces. As a result, reliability and assembly yields can be compromised.

The optimal profile must take into account the solder paste/flux used, the size of the board, the density of the components on the board, and the mix between large components and smaller, lighter components. Profiles should be established for all new board designs using thermocouples at multiple locations on the component. In addition, if there is a mixture of devices on the board, then the profile should be checked at various locations on the board. Ensure that the minimum reflow temperature is reached to reflow the larger components and at the same time, the temperature does not exceed the threshold temperature that might damage the smaller, heat sensitive components.

The following tables and figure provide guidelines for profiling Pb-free solder reflow. In general, a gradual, linear ramp into a spike has been shown by various sources to be the optimal reflow profile for Pb-free solders. This profile has been shown to yield better wetting and less thermal shock than conventional ramp-soak-spike profile for the Sn/Pb system. SnAgCu alloy reaches full liquidus temperature at 235°C. When profiling, identify the possible locations of the coldest solder joints and ensure that those solder joints reach a minimum peak temperature of 235°C for at least 10 seconds. Reflowing at high peak temperatures of 260°C and above can damage the heat sensitive components and cause the board to warp. Users should reference the latest IPC/JEDEC J-STD-020 standard for the allowable peak temperature on the component body. The allowable peak temperature on the component body is dependent on the size of the component. The table lists the peak package reflow body temperature information. In any case, use a reflow profile with the lowest peak temperature possible.



Table 21: Pb-Free Reflow Soldering Guidelines for Package Sizes Up to 45 mm x 45 mm

Profile Feature	Convection, IR/Convection	
Preheat ramp-up rate 30°-150°C	2°C/s maximum 1°C/s maximum for lidless packages with stiffener ring	
Preheat temperature soak time 150°-200°C	60–120 seconds	
Temperature maintained above 217°C	60–150 seconds (60–90 seconds typical)	
Time within 5°C of actual peak temperature	30 seconds maximum	
Peak temperature (lead/ball)	230°C–245°C typical (depends on solder paste, board size, component mixture)	
Maximum peak temperature (body)	240°C–250°C, package body size dependent (see the specific Versal ACAP Data Sheet).	
Ramp-down rate	2°C/s maximum	
Time 25°C to peak temperature	3.5 minutes minimum, 5.0 minutes typical, 8 minutes maximum	

Table 22: Pb-Free Reflow Soldering Guidelines for Package Sizes Greater than 45 mm x 45 mm and Up to 55 mm x 55 mm

Profile Feature	Convection, IR/Convection
Preheat ramp-up rate 30°-150°C	0.5°C/s-1.5°C/s
Preheat temperature soak time 150°-190°C	65–70 seconds
Temperature maintained above 217°C	50–60 seconds
Maximum peak temperature (body)	234°C–238°C, package body size dependent (see the specific Versal ACAP Data Sheet).
Ramp-down rate 240°–125°C	1°C/s-2°C/s

Table 23: Pb-Free Reflow Soldering Guidelines for Package Sizes Greater than 55 mm x 55 mm

Profile Feature	Convection, IR/Convection	
Preheat ramp-up rate 30°–150°C	0.5°C/s-1.5°C/s	
Preheat temperature soak time 150°-190°C	76–81 seconds	
Temperature maintained above 217°C	77–93 seconds	
Maximum peak temperature (body)	231°C–240°C, package body size dependent (see the specific Versal ACAP Data Sheet).	
Ramp-down rate 240°–185°C	0.7°C/s-0.8°C/s	
Ramp-down rate 185°–125°C	1.6°C/s-1.75°C/s	



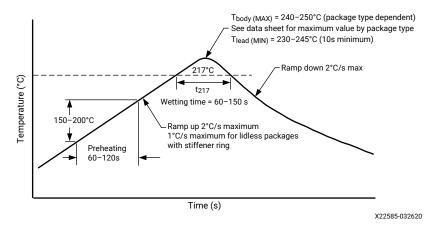


Figure 29: Typical Conditions for Pb-Free Reflow Soldering

Peak Package Reflow Temperatures

Table 24: Peak Package Reflow Body Temperature (Based on J-STD-020 Standard)

Package	Product Category	Peak Package Reflow Body Temperature ¹	JEDEC Moisture Sensitivity Level (MSL)	
SFVB625	All	Mass reflow: 250°C Dry rework: 260°C	4	
VBVA1024				
VFVB1024				
VFVB1369		Mass reflow: 240°C Dry rework: 260°C	4	
VSVE1369]			
VSVA1596	AII			
VIVA1596				
VFVA1760		Dry rework. 200 C		
VFVC1760				
VSVD1760				
VSVA2197				
VSVA2785				

Notes:

- 1. See the specific Versal ACAP Data Sheet for the most up-to-date specifications.
- 2. For devices with the Pb-free signifier in the package name (labeled as Q vs. V) use the temperatures and MSL listed for the XQ product category.

For sophisticated boards with a substantial mix of large and small components, it is critical to minimize the ΔT across the board (<10°C) to minimize board warpage and thus, attain higher assembly yields. Minimizing the ΔT is accomplished by using a slower rate in the warm-up and preheating stages.



It is also important to minimize the temperature gradient on the component, between top surface and bottom side, especially during the cooling down phase. The key is to optimize cooling while maintaining a minimal temperature differential between the top surface of the package and the solder joint area. The temperature differential between the top surface of the component and the solder balls should be maintained at less than 7°C during the critical region of the cooling phase of the reflow process. This critical region is in the part of the cooling phase where the balls are not completely solidified to the board yet, usually between the 200°C–217°C range. To efficiently cool the parts, divide the cooling section into multiple zones, with each zone operating at different temperatures.

The optimal profile must take into account the solder paste/flux used, the size of the board, the density of the components on the board, and the mix between large components and smaller, lighter components. Profiles should be established for all new board designs using thermocouples at multiple locations on the component. In addition, if there is a mixture of devices on the board, then the profile should be checked at various locations on the board, as shown in the following thermocouple pictures. Ensure that the minimum reflow temperature is reached to reflow the larger components and at the same time, the temperature does not exceed the threshold temperature that might damage the smaller, heat sensitive components.

Figure 30: Thermocouple Top

TOP Profile,

TC 1: U17 Edge 1
TC 2: U17 Edge 2
TC 3: U17 Edge 3
TC 4: U17 Edge 4
TC 5: U17 Middle 1
TC 6: U17 Middle 2
TC 7: U17 Body
TC 8: Q25
TC 9: U25







Figure 31: Thermocouple Bottom

Post Reflow/Cleaning/Washing

Many PCB assembly subcontractors use a no-clean process in which no post-assembly washing is required. Although a no-clean process is recommended, if cleaning is required, Xilinx recommends a water-soluble paste and a washer using a deionized-water. Baking after the water wash is recommended to prevent fluid accumulation. Cleaning solutions or solvents are not recommended because some solutions contain chemicals that can compromise the lid adhesive, thermal compound, or components inside the package.

Conformal Coating

Xilinx does not have information regarding the reliability of flip-chip BGA packages on a board after exposure to any specific conformal coating process. Therefore, any process using conformal coating should be qualified for the specific use case to cover the materials and process steps.

Ruggedized XQ packages are designed to support conformal coating, with vented lids that ensure proper cleaning can occur after the etching process and prior to conformal coating.





RECOMMENDED: When a conformal coating is required, Parylene-based material should be used to avoid potential risk of weakening the lid adhesive used in Xilinx packages.

Strain Gauge Measurement

Strain gauge measurements are recommended to be done at each process step that has the potential to cause excessive board flexing leading to solder joint cracking. Assembly processes where strain gauge measurements are recommended include:

- PCB router (during PCB loading/unloading into fixture and during the routing process)
- PTH solder assembly during top-catch loading/unloading
- Press fit assembly during press base and tooling loading/unloading and during machine pressing process
- DIMM memory (during PCB loading/unloading and during insertion/removal of DIMM)
- Heat-sink assembly process (during PCB loading/unloading and during entire screw assembly process)
- X-ray fixture (during PCBA loading/unloading)

Strain gauge measurements should be in the range of $\pm 500~\mu$ strain. Dye and pry analysis is required to confirm if the measured strain causes solder joint cracking. It is recommended to conduct dye and pry analysis for any strain reading greater than 500 μ strain. To reduce the affects of strain on a device, edge bonding can be used and is recommended for larger packages. See Chapter 10: Edge Bonding Guidelines for implementation details.

Solder Paste

Solder paste consists of solder alloy and a flux system. A typical solder paste composition by volume is split between about 50% alloy and 50% flux. The metal load mass (solder alloy powder) is around 90%, with the remaining 10% mass a flux system. The primary purpose of the flux system is to remove the contaminants from the solder joints during the soldering process. The capability of removing contaminants is determined by the activation level of the type of solder paste. The preferred solder paste metal alloy has a lead-free composition (SnAgCu where Ag is 3–4% and Cu is 0.5–1%). A no-clean solder paste is preferred to eliminate any risk of improper cleaning that could leave active residue beneath the device and other BTC components. The paste must be suitable for printing the solder stencil aperture dimensions. Type 4 paste is recommended for better paste release performance. When using a solder paste, you must adhere to the handling recommendations of the paste manufacturer.



Component Placement



IMPORTANT! The following component placement guidelines apply to all package types included in this guide (lidded, lidless, bare-die, etc.).

Xilinx device packages must be placed accurately according to their geometry outline. Positioning packages manually via hand mounting is not recommended. Typical component placement accuracies of $\pm 50~\mu m$ can be achieved using standard pick and place equipment with vision system. The PCB and components are optically checked and measured by the pick and place vision system. The pick and place machine detects the fiducial on the PCB immediately prior to the placement of the Versal device. Recognition of the packages is performed by the vision system, to ensure correct centering of the Versal device placement on the PCB pad array. BGA packages with solder balls can self-align during the reflow process because of the solder high surface tension that enables the pulling and centering of the device, and where a slight offset of the placement is still allowed. For guidance, the maximum tolerable offset of device placement is around 30% of the pad diameter on the PCB for typical non-solder mask defined pads. This means that the misalignment of solder ball device packages to the PCB pad must be better than 150 μ m to assure a robust mounting process. Generally, this is achievable using a wide range of modern pick and placement systems. The following setup conditions are important for the pick and placement systems:

- The pick and place nozzle type should be selected based on the dimensions of the Versal device. The nozzle needs to firmly hold the device package during the pick and place stage. The appropriate nozzle type for the device package can be chosen from the manual provided by the pick and place equipment manufacturer.
- The ball recognition capabilities of the placement system should be used and package outline centering should be avoided. This eliminates the solder ball to package edge tolerances of the package. Refer to the specific package outline drawing for details.
- To ensure the proper identification of the device package during vision recognition, prior to its placement, a suitable lighting system and the correct choice of the features of the measuring method are essential. The most suitable settings can be chosen from the manual provided by the pick and place equipment manufacturer.
- To avoid solder bridging or solder smear, ensure the proper placement force of the device package during placement on the PCB. Excessive placement force can lead to excess solder paste and cause solder bridging. However, a slight placement force can lead to insufficient solder paste contact between the device package solder balls and the solder paste, causing solder defects including open solder joints, badly centered packages, or even head-in-pillow (HIP) defects.

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Component Pick-up Tool Consideration

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Metal Pick Up Tip Nozzle with Soft Tips or Suction Cups is Preferred

For pick and place machines to place lidless and bare-die flip-chip BGAs onto PCBs, Xilinx recommends using soft tips or suction cups for the nozzles. This prevents chipping, scratching, or even cracking of the bare die.

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Metal Pick Up Tip Nozzle Can Damage the Exposed Silicon

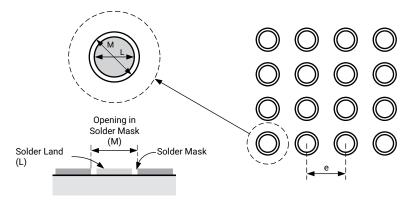
Figure 32: Recommended Method For Using Pick-up Tools



Recommended PCB Design Rules for BGA

Xilinx provides the diameter of a land pad on the package side. This information is required prior to the start of the board layout so the board pads can be designed to match the component-side land geometry. The typical values of these land pads are shown in the following figure and summarized in the table. For Xilinx BGA packages, non-solder mask defined (NSMD) pads on the board are suggested to allow a clearance between the land metal (diameter L) and the solder mask opening (diameter M) as shown in the following figure.

Figure 33: Suggested Board Layout of Soldered Pads for BGA Packages



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Table 25: BGA Package Design Rules

Flip-Chip BGA Packages	1.0 mm Pitch	0.92 mm Pitch	0.80 mm Pitch
Design Rule	BGA packages, non-solder mask defined dimensions in mm (mils)		
Package land pad opening (SMD)	0.53 mm (20.9 mils)	0.53 mm (20.9 mils)	0.40 mm (15.7 mils)
Maximum PCB solder land (L) diameter	0.53 mm (20.9 mils)	0.51 mm (20.0 mils)	0.40 mm (15.7 mils)
Opening in PCB solder mask (M) diameter	0.63 mm (24.8 mils)	0.61 mm (24.0 mils)	0.50 mm (19.7 mils)
Solder ball land pitch (e)	1.00 mm (39.4 mils)	0.92 mm (36.2 mils)	0.80 mm (31.5 mils)



An example of an NSMD PCB pad solder joint is shown in the following figure. The space between the NSMD pad and the solder mask, as well as the actual signal trace widths, depend on the capability of the PCB vendor. The cost of the PCB is higher when the line width and spaces are smaller.

- RECOMMENDED: Xilinx recommends not mixing PCB pad isolated via-in-pad plated over (VIPPO) and non-VIPPO design styles because they can cause hot-tear defects that are related to localized Z-direction thermal expansion coefficient mismatch between VIPPO and non-VIPPO vias. A VIPPO via expands less than a non-VIPPO via.
- RECOMMENDED: Xilinx recommends not mixing PCB pad of solder mask defined (SMD) and non-solder mask defined (NSMD) design styles, because this can cause solder bridging defects. For violation, customers need to work with their CM to optimize the stencil design and assembly process.
- RECOMMENDED: For packages with names beginning with V or L (e.g., VSVA2197 and LSVA3112), the region underneath the land-side capacitors (LSCs) should be covered by solder mask. If traces are routed on the PCB top layer within the LSC region, clearance space between the PCB traces/solder mask and the capacitors must be ensured. Typically, there is 0.13 mm of clearance between the seating plane (PCB) and the surface of the capacitors. Refer to Chapter 5: Mechanical Drawings for LSC locations and relevant dimensions for each package.

BGA Package

BGA Solder Ball

Solder Mask

PCB

M

X22596-040119

Figure 34: Example of an NSMD PCB Pad Solder Joint

Stencil

Solder paste is applied to PCB metal pads by screen printing. The volume of the printed solder paste is determined by the stencil aperture and the stencil thickness. In most cases, the thickness of a stencil must be matched to the needs of all components on the PCB. Stencil apertures should be a circular shape. To ensure a uniform and high-solder paste transfer to the PCB, laser-cut stencil, made from mostly stainless steel, is typically used. Nickel Blank stencils, referring to stencils where the entire foil is laser-cut from a sheet of pure nickel material, can also be used. However, high-quality nano-coated stencils (laser cut from stainless steel) can perform as well as or better than Nickel Blanks.



Uniform Stencil Aperture Design

- For packages with 0.92 mm ball pitch, a uniform stencil aperture opening of 19.7 mils to 20.0 mils round is recommended, matching the PCB pad size.
- For packages less than 55 mm x 55 mm with 1 mm ball pitch, a uniform stencil aperture opening of 19.7 mils to 20.0 mils round is also recommended.

Bull's Eye Stencil Recommendation

Another option is to use a *Bull's Eye* stencil aperture, where the board land-pad diameter increases from the center of the device outward, matching the variable aperture diameter of the stencil, at a rate that depends on the warpage as a function of thermal expansion and mechanical attachment. This can vary depending on the PCB. The bull's eye offers a capture margin, because with an increased opening size with respect to the outer BGA balls, more solder paste is printed. A recommended stencil design for the bull's eye design is shown in the following figure. Similar stencil designs are recommended for packages 55 mm x 55 mm and larger with 1 mm ball pitch. The final stencil design should be based on an evaluation of the board design. Designers should work with their CM to optimize the stencil design and assembly process.

- RECOMMENDED: Xilinx recommends using a 5 mil thick stencil.
- **RECOMMENDED:** Xilinx recommends using a uniform stencil aperture opening of 19.7 mils to 20 mils round, matching the PCB pad size for packages with 0.92 mm ball pitch.
- **RECOMMENDED:** Xilinx recommends using a uniform stencil aperture opening of 19.7 mils to 20 mils round, matching the PCB pad size for packages less than 55 mm x 55 mm with 1.0 mm ball pitch.
- **RECOMMENDED:** Xilinx recommends using a non-uniform (bull's eye) stencil aperture opening for packages 55 mm x 55 mm and larger with 1.0 mm ball pitch.



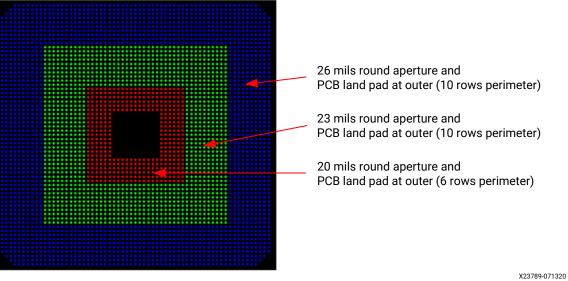


Figure 35: Bull's Eye Stencil Aperture





Edge Bonding Guidelines

The edge bonding technique uses high-adhesion adhesives dispensed along the periphery of a component, as shown in the following figure. Xilinx recommends edge bonding larger packages ($55 \text{ mm} \times 55 \text{ mm}$ or larger) for increased mechanical reliability.

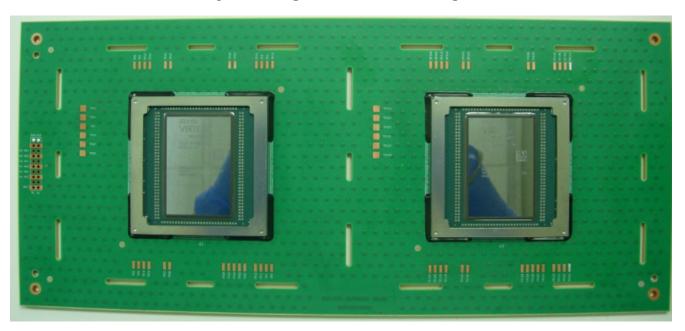


Figure 36: Edge Bonded BGA Packages

Edge Bonding Implementation

Edge bonding is the dispensing of an epoxy material around the periphery of the package after board mount. Xilinx requires the use of the Zymet UA-2605-B edge-bonding material. Edge bonding is not intended to under fill the package or contact the solder balls. This technique allows for component rework and improves the robustness of the mounted component by controlling the expansion and warpage of the board during normal operating conditions To place the adhesive while using an in-line soldering robot, Xilinx recommends the parameters shown in the following table.



Table 26: Process Parameters for Edge Bonding

Process Parameter	Range Specification	
Needle size	Range: 25 - 18 gauge Recommended: 18 gauge	
Needle height	Range: Above the device edge midpoint, or 0 to 1.5 mm below the top surface of the device Recommended: 1.0 mm below the top surface of the device	
Needle edge spacing	Range: Half to three quarters of needle outer diameter (D) Recommended: Half of needle diameter (D/2), approximately 1.0 mm D/2 to 3/4D	
Dispense needle speed	Range: 0.1 to 200 mm/second Recommended: 9 mm/second	
Value pressure	Range: 20 to 60 psi Recommended: 1.2 kgf/cm² @17 psi	

The adhesive is dispensed along the perimeter of the assembled component at a width of 3 mm and a height of 50% to 90% the substrate height, leaving a small section at the center of each edge unbonded, as illustrated in the following figure. This is to ensure that there is an outlet for any expansion of the air during processing. Xilinx recommends centering the opening on each side with a width of 25–30% the length of the package substrate. The exact locations and size of the openings can be varied depending on the design and rework.



PCB No test points under adhesive placement keep-out locations. Opening ~30-50% of substrate length Adhesive bead must be continuous and maintain **BGA** uniform contact to both the length of the substrate and the PCB solder mask surface. Adhesive Length (L) Typically 25%-35% of Adhesive Width (W) substrate length from Extends ~3 mm from the corner the device Adhesive Height Too Little Correct Too Much 50% to 90% of BGA substrate height Minimize the amount of adhesive under the substrate X23787-032620

Figure 37: Edge Bonding Adhesive Placement Parameters



RECOMMENDED: Curing conditions are 155° C for 10 minutes.

Component Clearance Surrounding Edge Bond

An adjacent component clearance surrounding the Xilinx device is necessary to have the 30° to 45° angle required for the edge bond dispenser to dispense the edge bond adhesive material. The surrounding component height and distance from the device is validated based on each unique product design layout.



Edge Bond Removal

Edge bond material can be removed by heating to 170–180°C, and scraping using a stiff probe made of stable organic material such as a non-resinous wood or Teflon. Use a hot air blower on the edge bond area and slowly remove the edge bond adhesive from side to side. Do not use force to remove the edge bond adhesive. Excess adhesive on the PCB can be removed using a chisel-tip soldering iron, with sufficient precautions to limit damage to the PCB surface.

Xilinx has successfully evaluated the application processes used by Flex and Celestica and recommends these contract manufacturers for edge bond assembly of Xilinx packages.

- https://flex.com/
- https://www.celestica.com/





Thermal Specifications

Versal™ ACAPs are offered exclusively in thermally efficient flip-chip BGA packages. These flip-chip packages range in pin-count from the smaller 21 × 21 mm SFVB625 to the 52.5 × 52.5 mm VSVA2197. This suite of packages is used to address the various power requirements of the Versal ACAPs. Versal devices are implemented in the 7 nm process technology. Unlike features in an ASIC, the combination of Versal ACAP features used in a user application is not known to the component supplier. Therefore, it remains a challenge for Xilinx to predict the power requirements of a given Versal device when it leaves the factory. Accurate estimates are obtained when the board design takes shape. For this purpose, Xilinx offers and supports a suite of integrated device power analysis tools to help users quickly and accurately estimate their design power requirements. Versal ACAPs are supported similarly to previous products. The uncertainty of design power requirements makes it difficult to apply canned thermal solutions to fit all users. Therefore, Xilinx devices do not come with preset thermal solutions. The operating conditions of your design dictate the appropriate solution.

Support for Thermal Models

Xilinx offers and supports a suite of integrated device power analysis tools to help you quickly and accurately estimate your design power requirements.

The variability of design power requirements makes it difficult to apply pre-determined thermal solutions to fit all designs. The estimated power of the device using XPE, coupled with the your operating conditions and system constraints, dictate the appropriate solution. You must establish a thermal margin to account for the impact of the following (but not limited to) variations.

- Impact of the thermal sensor accuracy
- Impact of the power variation from one package to another package
- Impact of the manufacturing variation between fans
- Impact of the manufacturing variation between heat-sink fins
- Impact of the package manufacturing variation between heat-sink flatness
- Impact of the manufacturing variation of heat sink TIM contact/thickness

For example, when targeting maximum junction temperature (100°C) minus 8°C you must account for any additional system/environmental errors.



The detailed thermal model is a direct representation of the specified FCBGA package. The model provides geometric details describing the package, specifically in regards to the lid, TIM, die, underfill, substrate, and solder balls or leads. Each specific component in the detailed model has material properties associated. When using this detailed model, several key facts must be considered:

- Two variations of the detailed thermal model are provided: Full detailed thermal model and simplified thermal model.
- The full detailed thermal model provides all the intricate geometries representing the physical package and can be used for mechanical evaluation of the device. However, it should not be used to perform thermal simulations because the detailed geometries create a large meshing size and high-computation time with little to no increase in overall accuracy.
- The simplified detailed model removes certain geometries including substrate trace layers and stiffener ring that do not have a material impact on thermal simulation accuracy and significantly increase computational time. This simplified model provides a much smaller meshing size and less computation time for simulation with less than a 5% difference in simulation accuracy from the full detailed model.
- The correct package top surface contact must be used when modeling the TIM on top of the detailed model because the top surface contact might not be the actual full package size.
- The junction temperature monitor point is at the die center by default. Junction temperature monitor points need to be positioned or added to the location of interest for your design.
- The uniform power defined in the die for the models provided is default power and does not apply to any specific cases. Power setting input is required.





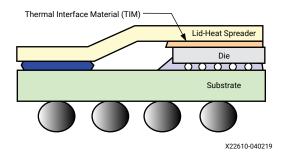
Thermal Management Strategy

Xilinx relies on a multi-pronged approach to consuming less power and dissipating heat for systems using devices.

Flip-Chip Packages

Versal[™] devices are offered in flip-chip BGA packages, which present a low thermal path. Packages primarily consist of lidless with stiffener ring variations, with the exception of the bare-die packages and lidded packages incorporating a heat spreader with an additional thermal interface material (TIM), as shown in the following figure.

Figure 38: Heat Spreader with Thermal Interface Material



Materials with high thermal conductivity and consistent process are expected to be used to deliver low thermal resistance to a heat sink, and are included in lidded packages with a heat spreader. An effort to ensure optimized package electrical return paths produces the added benefit of enhanced power and ground plane arrangement in the packages. A boost in copper density on the planes improves the overall thermal conductivity through the laminate. In addition, the extra dense and distributed via fields in the package increase the vertical thermal conductivity.



System Level Heat Sink Solutions

To complete a comprehensive thermal management strategy, an overall thermal budget that includes custom or OEM heat sink solutions depends on the physical and mechanical constraints of the system. A heat-sink solution, managed by the system-level designer, should be tailored to the design and specific system constraints. This includes understanding the inherent device capabilities for delivering heat to the surface.

By considering the system's physical, mechanical, and environmental constraints, the overall thermal budget is maintained and does not exceed the device's maximum operating temperature. The heat sink is an integral part of the thermal management solution to maintain a safe operating temperature. As a result, the system-level designer must be aware of the following:

- For lidless packages, the nominal stiffener height can be different from the height of the die. Therefore, the heat sink must have an island to contact the die.
- Especially for lidless packages, Run thermal simulations of the system in worst-case environmental conditions using detailed thermal models, which accurately represent the device thermal performance under all boundary conditions.
- Consider the mechanical specifications of the package as well as the selection of the thermal interface between the die and the thermal management solution to ensure the lowest thermal contact resistance.
- The total thermal contact of the thermal interface material is determined based on parameters from the data sheet supplied by the thermal interface manufacturer.
- See the applied pressure recommendation section. Lower pressure runs the risk of poor thermal contact and higher pressure runs the risk of damaging the device; therefore, strict control of pressure is required. The use of a smart-torque tool is suggested when applying a heat sink to control the rate of short-term transient pressure as the thermal interface material (TIM) relaxes. Specifications from the TIM supplier should be taken into consideration.
- Consider all uncertainties in thermal modeling, including manufacturing variations from the thermal solutions (for example, fan airflow tolerance, heat pipe or vapor chamber performance tolerance, variation of the attachment of fins to heat sink base, and surface flatness).

Thermal Interface Material

When installing heat sinks for Versal devices, a suitable thermal interface material (TIM) must be used. This thermal material significantly aids the transfer of heat from the component to the heat sink.



For lidless and bare-die flip-chip BGAs, the surface of the silicon contacts the heat sink. For lidded flip-chip BGAs, the lid contacts the heat sink. The surface size of the lidless or bare-die flip-chip BGA and lidded flip-chip BGAs are different. Xilinx recommends a different type of thermal material for long-term use with each type of flip-chip BGAs package.

Thermal interface material is needed because even the largest heat sink and fan cannot effectively cool an Versal device unless there is good physical contact between the base of the heat sink and the top of the Versal device. The surfaces of both the heat sink and the Versal device silicon are not absolutely smooth. This surface roughness is observed when examined at a microscopic level. Because surface roughness reduces the effective contact area, attaching a heat sink without a thermal interface material is not sufficient due to inadequate surface contact.

A thermal interface material such as phase-change material, thermal grease, or thermal pads fills these gaps and allows effective transference of heat between the Versal device die and the heat sink.

The selection of the thermal interface material (TIM) between the package and the thermal management solution is critical to ensure the lowest thermal contact resistance. Therefore, the following parameters must be considered.

- 1. The flatness of the lid and the flatness of the contact surface of the thermal solution.
- 2. The applied pressure of the thermal solution on the package, which must be within the allowable maximum pressure that can be applied on the package. The use of a smart-torque tool is suggested when applying a thermal solution to control the rate of short-term transient pressure as the TIM material relaxes. Specifications from the TIM supplier should be taken into consideration.
- 3. The total thermal contact of the thermal interface material. This value is determined based on the parameters in step 1 and step 2, which are published in the data sheet of the TIM supplier.

Types of TIM

There are many type of TIM available for sale. The most commonly used thermal interface materials are listed.

- Thermal grease
- Thermal pads
- Phase change material
- Thermal paste
- Thermal adhesives
- Thermal tape



Guidelines for Thermal Interface Materials

Five factors affect the choice, use, and performance of the thermal interface material (TIM) used between the device and the heat sink. Each factor is discussed in this section.

- Thermal conductivity of the material
- Electrical conductivity of the material
- Spreading characteristics of the material
- Long-term stability and reliability of the material
- Ease of application
- Applied pressure from heat sink to the package through the TIM

Thermal Conductivity of the Material

Thermal conductivity is the quantified ability of any material to transfer heat. The thermal conductivity of the interface material has a significant impact on its thermal performance. The higher the thermal conductivity, the more efficient the material is at transferring heat. Materials that have a lower thermal conductivity are less efficient at transferring heat, causing a higher temperature differential to exist across the interface. To overcome this less efficient heat transfer, a better cooling solution (typically, a more costly solution) must be used to achieve the desired heat dissipation.

Electrical Conductivity of the Material

Some metal-based TIM compounds are electrically conductive. Ceramic-based compounds are typically not electrically conductive. Manufacturers produce metal-based compounds with low-electrical conductivity, but some of these materials are not completely electrically inert. Metal-based thermal compounds are not hazardous to the Versal ACAP die itself, but other elements on the Versal device or motherboard can be at risk if they become contaminated by the compound. For this reason, Xilinx does not recommend the use of electrically conductive thermal interface material.

Spreading Characteristics of the Material

The spreading characteristics of the thermal interface material determines its ability, under the pressure of the mounted heat sink, to spread and fill in or eliminate the air gaps between the Versal device and the heat sink. Because air is a very poor thermal conductor, the more completely the interface material fills the gaps, the greater the heat transference.



Long-Term Stability and Reliability of the Material

The long-term stability and reliability of the thermal interface material is described as the ability to provide a sufficient thermal conductance even after an extended time or extensive. Low-quality compounds can harden or leak out over time (the pump-out effect), leading to overheating or premature failure of the Versal device. High-quality compounds provide a stable and reliable thermal interface material throughout the lifetime of the device. Thermal greases with higher viscosity are typically more resistant to pump out effects on bare-die devices.

Ease of Application

A spreadable thermal grease requires the surface mount supplier to carefully use the appropriate amount of material. Too much or too little material can cause problems. The thermal pad is a fixed size and is therefore easier to apply in a consistent manner.

Applied Pressure from Heat Sink to the Package via Thermal Interface Materials

Measure applied pressure using a calibrated pressure sensor on multiple locations between the device and the heat sink assembly as shown in the following figure.

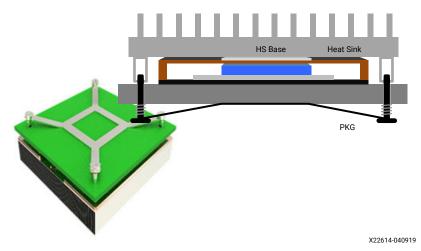


Figure 39: Pressure Sensor



- RECOMMENDED: Xilinx recommends that the applied pressure on the package be in the range of 20 to 50 PSI for optimum performance of the TIM between the package and the heat sink. Thermocouples should not be present between the package and the heat sink, as their presence will degrade the thermal contact and result in incorrect thermal measurements. The best practice is to select the appropriate pressure (in the 20 to 50 PSI range) for the optimum thermal contact performance between the package and the thermal system solution, and the mechanical integrity of the package (with the thermal solution to pass all mechanical stress and vibration qualification tests). The use of a smart-torque tool is suggested when applying a heat sink to control the rate of short-term transient pressure as the TIM material relaxes. Specifications from the TIM supplier should be taken into consideration.
- TIP: These recommendations and specifications are the same for both lidded and lidless devices.
- **RECOMMENDED:** Xilinx recommends using dynamic mounting around the four corners of the device package. On the PCB, use a bracket clip as part of the heat sink attachment to provide mechanical package support. See the following figure.

Figure 40: Dynamic Mounting and Bracket Clips on Heat Sink Attachment



Heat Sink Removal

When removing or reworking heat sinks, the phase-change material residue must be removed from the surface of the die. Laird Technologies, Inc. provides the following guidance for complete removal of the phase-change material from the component.

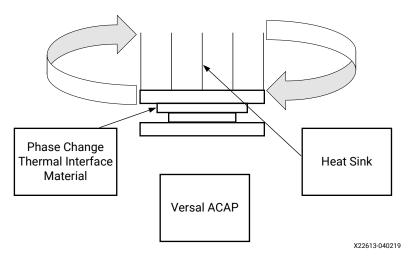
Instructions for Removal of Phase-change Material

1. Separate the Components



At room temperature, if possible, use a back and forth twisting motion to break the bond between the phase-change thermal interface material and mated components (i.e., heat sink and Versal device). See the following figure.

Figure 41: Breaking the Bond between Thermal Interface Material and Mated Components



For smaller components (typically 15 mm x 15 mm or less), the bond usually breaks free easily at room temperature. For larger components, in situations where minimal movement is available, or if using fragile components, heat the component (preferred) or heat sink to about $40^{\circ}\text{C}-60^{\circ}\text{C}$ before removal.

The guideline is 40°C-60°C, however, you might find that for your application, heating to 35°C is adequate. You might prefer to heat to 70°C which makes the phase-change thermal interface material very soft and the components can be easily separated.

2. Scrape Away Thick Residue

For a faster clean-up once components are separated, scrape away any large residual material amounts with a plastic spatula or a wooden tongue depressor. A clean dry rag can be used to wipe away excess material.

3. Clean Remaining Residue with Solvent

Using a clean cloth/wipe, wet it with your choice of solvent (see the following list) and wipe away any remaining residue.

- Toluene (easiest)
- Acetone (very good)
- Isoparaffinic hydrocarbon: Isopar, Soltrol (trade names) (very good)
- Isopropyl alcohol (OK)
- 4. Working with Laird Material



Safe handling, disposal, and first-aid measures for working with phase-change material are included in the Laird Technologies material safety data sheet (MSDS). Read the MSDS before using or handling. See the Laird Technologies, Inc. website.

Measurement Debug

When performing in-system thermal testing, to ensure accurate data and not incur damage to the device, do not place a thermocouple in between the device and the heat sink. On the extreme side, it might cause additional mechanical and/or thermal stress to the device, leading to damage. Even if damage does not occur, it often leads to a thicker and or uneven thermal interface material thickness, leading to a thermal performance difference from a system without a thermocouple. To obtain the device temperature, use the System Monitor as a non-invasive means to get accurate device measurements while debugging the system.



Heat Sink Guidelines for Bare-die VB Packages

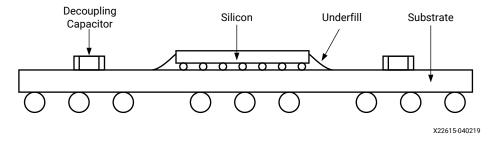
Heat Sink Attachments

Heat sinks can be attached to the package in multiple ways. For heat to dissipate effectively, the advantages and disadvantages of each heat sink attachment method must be considered. Factors influencing the selection of the heat sink attachment method include the package type, contact area of the heat source, and the heat sink type.

Silicon and Decoupling Capacitors Height Consideration

When designing heat sink attachments for bare-die flip-chip BGA packages, the height of the die above the substrate and also the height of decoupling capacitors must be considered (see the following figure). This is to prevent electrical shorting between the heat sink (metal) and the decoupling capacitors.

Figure 42: Cross Section of Bare-die Flip-chip BGA





Types of Heat Sink Attachments

There are six main methods for heat sink attachment. The following table lists their advantages and disadvantages.

- Thermal tape
- Thermally conductive adhesive or glue
- Wire form Z-clips
- Plastic clip-ons
- Threaded stand-offs (PEMs) and compression springs
- Push-pins and compression springs

Table 27: Heat Sink Attachment Methods

Attachment Method	Advantages	Disadvantages
Thermal tape	 Generally it is easy to attach and is inexpensive Lowest cost approach for aluminum heat sink attachment No additional space required on the PCB 	The surfaces of the heat sink and the chip must be very clean to allow the tape to bond correctly Because of the small contact area, the tape might not provide sufficient bond strength Tape is a moderate to low thermal conductor that could affect the thermal performance
Thermally conductive adhesive or glue	 Outstanding mechanical adhesion Somewhat inexpensive, costs a little more than tape No additional space required on the PCB 	 Adhesive application process is challenging and it is difficult to control the amount of adhesive to use. Difficult to rework Because of the small contact area, the adhesive might not provide sufficient bond strength
Wire form Z-clips	 It provides a strong and secure mechanical attachment. In environments that require shock and vibration testing, this type of strong mechanical attachment is necessary. Easy to apply and remove. Does not cause the semiconductors to be destroyed (epoxy and occasionally tape can destroy the device). It applies a preload onto the thermal interface material (TIM). Preloads actually improve thermal performance. 	Requires additional space on the PCB for anchor locations
Plastic clip-ons	 Suitable for designs where space on the PCB is limited Easy to rework by allowing heat sinks to be easily removed and reapplied without damaging the PCB board Can provide a strong enough mechanical attachment to pass shock and vibration test 	Needs a keep out area around the silicon devices to use the clip Caution is required when installing or removing clip-ons because localized stress can damage the solder balls or chip substrate



Table 27: Heat Sink Attachment Methods (cont'd)

Attachment Method	Advantages	Disadvantages
Threaded stand-offs (PEMs) and compression springs	Provides stable attachments to heat source and transfers load to the PCB, backing plate, or chassis	Holes are required in the PCB taking valuable space that can be used for trace lines
	Suitable for high mass heat sinksAllows for tight control over mounting force and load placed on chip and solder balls	Tends to be expensive, especially because holes need to be drilled or predrilled onto the PCB board to use stand-offs
Push-pins and compression springs	Provides a stable attachment to a heat source and transfers load to the PCB	Requires additional space on the PCB for push-pin locations
	Allows for tight control over mounting force and load placed on chip and solder balls	

Heat Sink Attachment Process Considerations

After the component is placed onto the PCBs, when attaching a heat sink to the bare-die package, the factors in the following table must be carefully considered (as shown in the following figure).

Table 28: Heat Sink Attachment Considerations

Consideration(s)	Effect(s)	Recommendation(s)
In a heat sink attach process, what factors can cause damage to the exposed die and passive capacitors?	 Uneven heat sink placement Uneven TIM thickness Uneven force applied when placing heat sink placement 	 Even heat sink placement Even TIM thickness Even force applied when placing heat sink placement
Does the heat sink tilt or tip the post attachment?	Uneven heat sink placement will damage the silicon and can cause field failures	 Careful handling not to contact the heat sink with the post attachment Use a fixture to hold the heat sink in place with post attachment until it is glued to the silicon



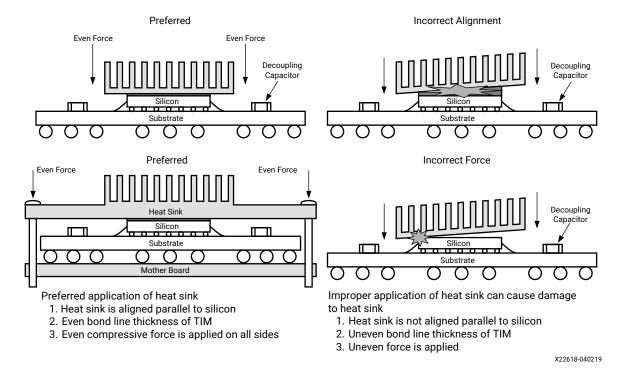


Figure 43: Recommended Application of Heat Sink

Standard Heat Sink Attach Process with Thermal Conductive Adhesive

Prior to attaching the heat sink, the Versal device needs be surface mounted on the motherboard.

- 1. Place the motherboard into a jig or a fixture to hold the motherboard steady to prevent any movement during the heat sink attachment process.
- 2. Thermoset material (electrically non-conductive) is applied over the backside surface of silicon in a pattern using automated dispensing equipment. Automated dispensers are often used to provide a stable process speed at a relatively low cost. The optimum dispensing pattern needs to be determined by the SMT supplier.

Note: Minimal volume coverage of the backside of the silicon can result in non-optimum heat transfer

- 3. The heat sink is placed on the backside of the silicon with a pick and place machine. A uniform pressure is applied over the heat sink to the backside of the silicon. As the heat sink is placed, the adhesive spreads to cover the backside silicon. A force transducer is normally used to measure and limit the placement force.
- 4. The epoxy is cured with heat at a defined time.

Note: The epoxy curing temperature and time is based on manufacturer's specifications.



Standard Heat Sink Attach Process with Thermal Adhesive Tape

Prior to attaching the heat sink, the Versal device needs be surface mounted on the motherboard.

- 1. Place the motherboard into a jig or a fixture to hold the motherboard steady to prevent any movement during the heat sink attachment process.
- 2. Thermal adhesive tape cut to the size of the heat sink is applied on the underside of the heat sink at a modest angle with the use of a squeegee rubber roller. Apply pressure to help reduce the possibility of air entrapment under the tape during application.
- 3. The heat sink is placed on the backside of the silicon with a pick and place machine. A uniform pressure is applied over the heat sink to the backside of the silicon. As the heat sink is placed, the thermal adhesive tape is glued to the backside of the silicon. A force transducer is normally used to measure and limit the placement force.
- A uniform and constant pressure is applied uniformly over the heat sink and held for a defined time.

Note: The thermal adhesive tape hold time is based on manufacturer's specifications.

Push-Pin and Shoulder Screw Heat Sink Attachment Process with Phase Change Material (PCM) Application

Prior to attaching the heat sink, the Versal device needs be surface mounted on the motherboard.

- 1. Place the motherboard into a jig or a fixture to hold the motherboard steady to prevent any movement during the heat sink attachment process.
 - Note: The jig or fixture needs to account for the push pin depth of the heat sink.
- 2. PCM tape, cut to the size of the heat sink, is applied on the underside of the heat sink at a modest angle with the use of a squeegee rubber roller. Apply pressure to help reduce the possibility of air entrapment under the tape during application.
- 3. Using the push-pin tool, heat sinks are applied over the packages ensuring a pin locking action with the PCB holes. The compression load from springs applies the appropriate mounting pressure required for proper thermal interface material performance.
 - **Note:** Heat sinks must not tilt during installation. This process cannot be automated due to the mechanical locking action which requires manual handling. The PCB drill hole tolerances need to be close enough to eliminate any issues concerning the heat sink attachment.



Mechanical and Thermal Design Guidelines for Lidless Flip-chip Packages

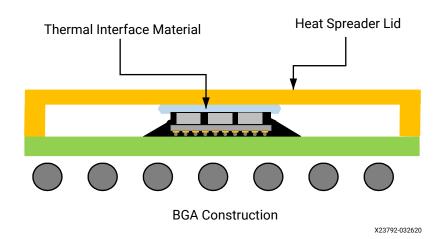
This section discusses the challenges of thermal management including reducing device thermal resistance and optimal power dissipation without an increase in junction temperature. The lidless Versal ACAP packages target the largest devices while allowing for cooler operation temperatures (up to 10°C) with the same power dissipation. Precise mechanical design and component thermal management is vital for device and system performance. This document presents the unique thermal and mechanical design requirements for lidless devices.

Lidless Flip-Chip Packages

The Xilinx flip-chip BGA packages exhibit a low-resistance thermal path that adequately cools devices. These packages incorporate a heat spreader lid with additional thermal interface material as shown in the following figure.

Figure 44: Flip-Chip BGA Construction with Heat Spreader and Thermal Interface

Material

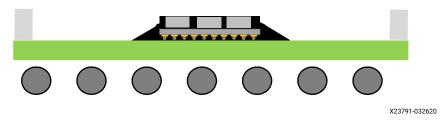




Materials with high thermal conductivity and consistent process applications deliver low thermal resistance up to the heat spreader. A parallel effort to ensure optimized package electrical return paths produces an enhanced power and ground plane arrangement in the package. A boost in copper density on the planes improves the overall thermal conductivity through the laminate. The extra density and distribution via fields in the package also increases the vertical thermal conductivity.

The lidless packages (see the following figure) offer the same package substrate design with electrical and board thermal conductivity similar to the flip-chip BGA packages. However, removing the lid (heat spreader) and the thermal interface material allows for direct contact between the external heat sink and the die. This further reduces the thermal resistance and exhibits improved thermal behaviors. The use of custom passive or active heat-sink designs is facilitated by incorporating two-phase (heat pipe, vapor chamber, or even liquid) cooling methods directly adjacent to the source of the dissipated heat on the die, which allows for a more efficient means of removing the heat from the device. Consequently, the device can operate at higher ambient temperatures while in area-constrained surroundings resulting in operational power advantages.

Figure 45: Lidless Flip-Chip BGA Construction



A unique feature of lidless packages is the addition of a stiffener ring around the periphery of the package substrate, providing additional package rigidity and helping to improve the overall package coplanarity (flatness). It also serves as a guide for the heat sink solution applied to the device. For examples, see the VSVD1760 Package—VC1802, VC1902, and VM1802 or VSVA2197 Package—VC1802, VC1902, and VM1802. In the lidless packages, capacitors can be placed in the area surrounding the die. Contact with electrically conductive materials must be avoided because the die-side capacitors, which are only slightly shorter than the die height, could be electrically conductive. Any thermal and mechanical solution higher than the die must not interfere with the package stiffener. Therefore, the thermal solution must have an island, see System Level Heat Sink Solutions. For further guidelines on mechanical and thermal designs of lidless packages, refer to Mechanical and Thermal Design Guidelines for Lidless Flip-Chip Packages (XAPP1301).





Additional Resources and Legal Notices

Xilinx Resources

For support resources such as Answers, Documentation, Downloads, and Forums, see Xilinx Support.

Documentation Navigator and Design Hubs

Xilinx® Documentation Navigator (DocNav) provides access to Xilinx documents, videos, and support resources, which you can filter and search to find information. To open DocNav:

- From the Vivado[®] IDE, select Help → Documentation and Tutorials.
- On Windows, select Start → All Programs → Xilinx Design Tools → DocNav.
- At the Linux command prompt, enter docnav.

Xilinx Design Hubs provide links to documentation organized by design tasks and other topics, which you can use to learn key concepts and address frequently asked questions. To access the Design Hubs:

- In DocNav, click the **Design Hubs View** tab.
- On the Xilinx website, see the Design Hubs page.

Note: For more information on DocNay, see the Documentation Navigator page on the Xilinx website.



References

These documents provide supplemental material useful with this guide:

- 1. Versal ACAP data sheets:
 - Versal Architecture and Product Data Sheet: Overview (DS950)
 - Versal Prime Series Data Sheet: DC and AC Switching Characteristics (DS956)
 - Versal AI Core Series Data Sheet: DC and AC Switching Characteristics (DS957)
- 2. Versal ACAP SelectIO Resources Architecture Manual (AM010)

Heat Management and Contact Information

The following websites contain additional information on heat management and contact information.

- Wakefield
- Boyd/Aavid
- Advanced Thermal Solutions
- Radian Thermal Products
- Thermo Cool
- CTS

Interface Material Sources

- Henkel
- AOS Thermal Compound
- Parker Chomerics
- Kester

CDF Tools

Refer to the following websites for CFD tools Xilinx supports with thermal models.

- Mentor Flotherm
- ANSYS Icepak

Thermal Modeling References

The following papers are referenced for more information on thermal modeling.



- Lemczyk, T.F., Mack, B., Culham, J.R. and Yovanovich, M.M., 1992, "Printed Circuit Board Trace Thermal Analysis and Effective Conductivity", ASME J. Electronic Packaging, Vol. 114, pp. 413 - 419.50.
- Refai-Ahmed, G. and Karimanal, K., 2003, "Validation of Compact Conduction Models of BGA Under Realistic Boundary," J. of Components and Packaging Technology, Vol. 26, No. 3, pp. 610-615.
- Sansoucy, E, Refai-Ahmed, G., and Karimanal, K., 2002, "Thermal Characterization of TBGA Package for an integration in Board Level Analysis," Eighth Intersociety on Thermal Conference Phenomena in Electronic Systems, San Diego., USA.
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- Karminal, K. and Refai-Ahmed, G., 2001, "Compact conduction Model (CCM) of Microelectronic Packages- A BGA Validation Study," APACK Conference on Advances in Packaging, Singapore.

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